

# Recent advances in silicon photonics

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life.augmented

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## 1. Silicon photonics: motivation

## 2. Optoelectronic devices

- Photodetection
- Optical modulation
- Optical laser source

## 3. Electronic-photonic convergence

## 4. Conclusion



FTTH



Optical telecommunications



Environment



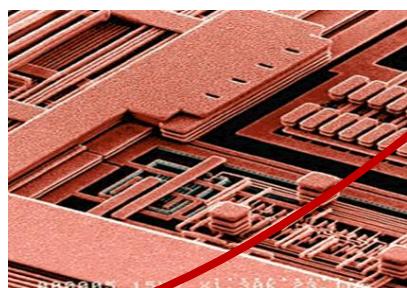
Data centers



Silicon photonics



Chemical/Biological sensors



Interconnects



Free space communications



Military

Source: L.Oxenlowe, Denmark



Courtesy: D. Moss, CUDOS, Australia

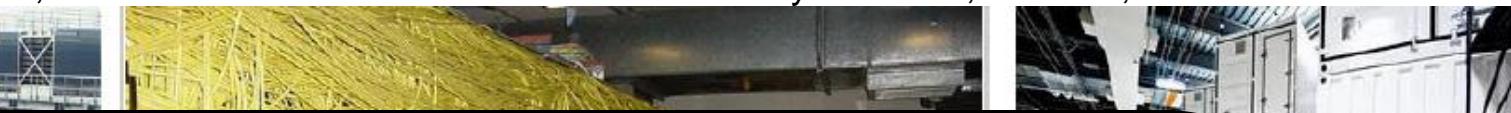


VIDEO!!!  
Data centre web services  
On-line games, File sharing  
TV/audio juke box ... more to come !!



Source: L.Oxenlowe, Denmark

Courtesy: D. Moss, CUDOS, Australia



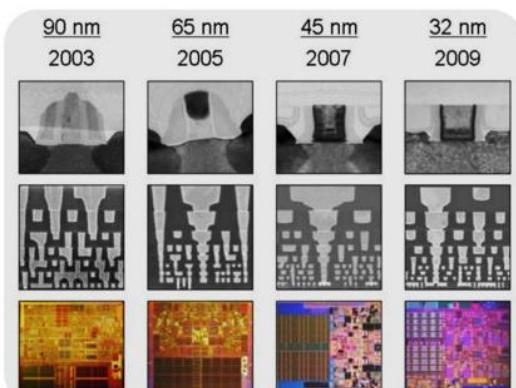
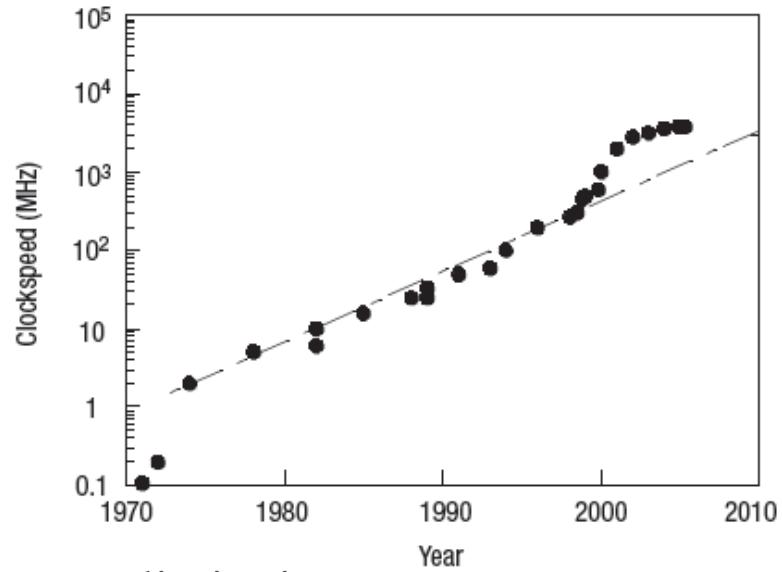
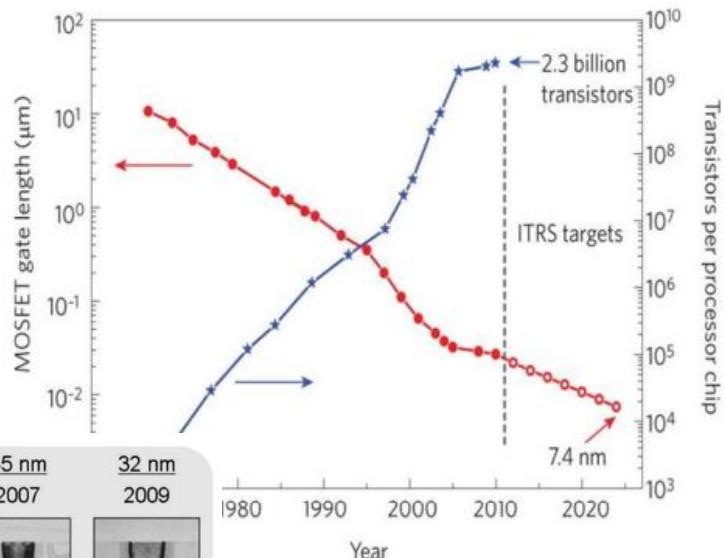
Facebook launches Arctic data centre



## Increase of integrated circuit complexity

- ✓ Number of transistors
- ✓ Frequency operation
- ✓ Length and density of metallic interconnects

Source: ITRS and Intel



### Metallic interconnect limitations

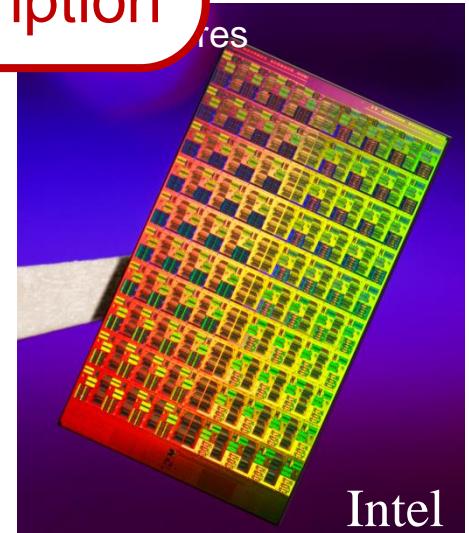
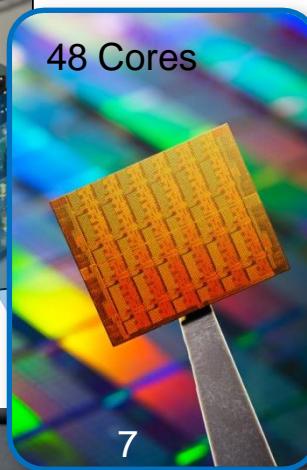
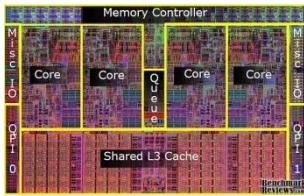
- RC delay
- Signal distortion
- Power consumption

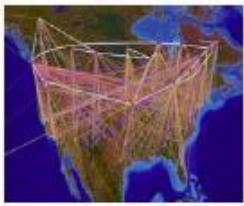
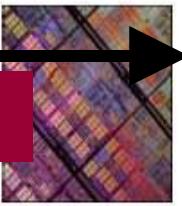
$$\text{Performance} = \text{Parallelism} \times \text{Frequency}$$

Use photonics at the chip scale to:

- New memory
  - More cores
- Increase the data transmission
  - Reduce the power consumption

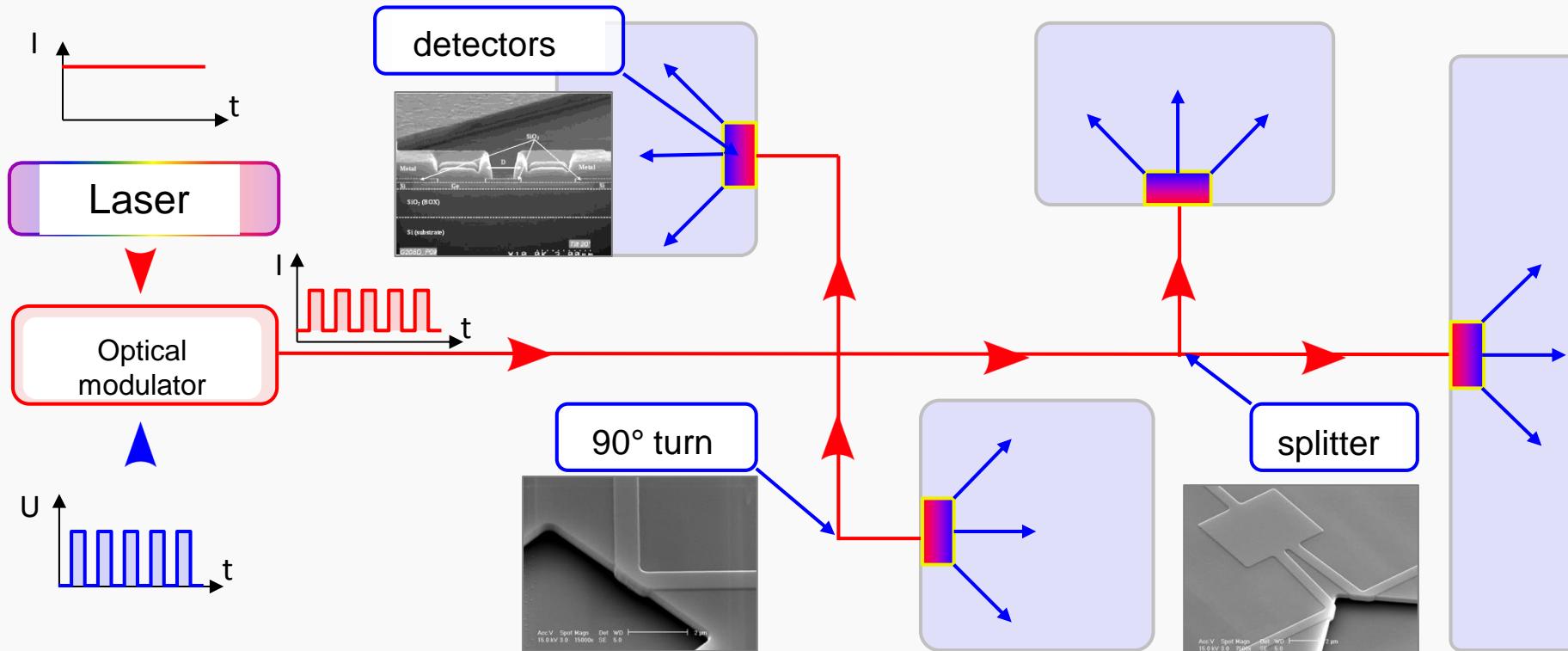
Example:



|                 | Internet, Wide Area Network   | Local Area Network  | Rack-to-Rack   | Card-to-Card  | On-Card   | On-MCM  | On-Chip  |
|-----------------|---|---|--|---|---|---|----------|
|                 |  |  |  |  |  |  |          |
| Distance        | > 100 km  | 10 - 2000 m   | 20 cm  | 0.1 - 0.2 mm  | 5 - 100 mm  | 0.1 - 10 mm   |          |
| Number of lines | 1   | 1 - 10  | ~100   | ~100-1000   | ~1000   | ~10'000   | ~100'000 |

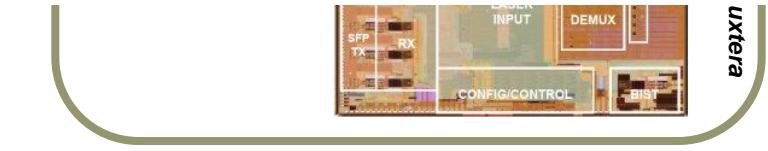
Source: IBM

# Photonics



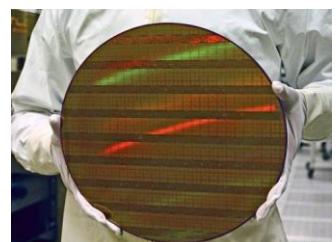
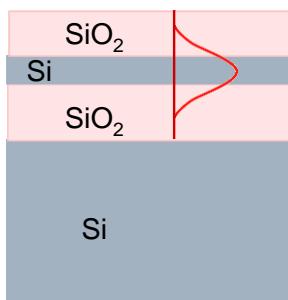
Silicon photonics

# CMOS Analoga





- Transparent in 1.3-1.6  $\mu\text{m}$  region
  - ✓ Low loss waveguides
- Take advantage of CMOS platform
  - ✓ Mature technology
  - ✓ High production volume
- Low cost
- Silicon On Insulator (SOI) wafer
  - ✓ Natural optical waveguide
- High-index contrast ( $n_{\text{Si}}=3.5 - n_{\text{SiO}_2}=1.5$ )
  - ✓ Strong light confinement
    - Small footprint (450nm x 220nm)



# Higher refractive index contrast, smaller cores, tighter bends



*Downscaling of photonics*

Silica on silicon

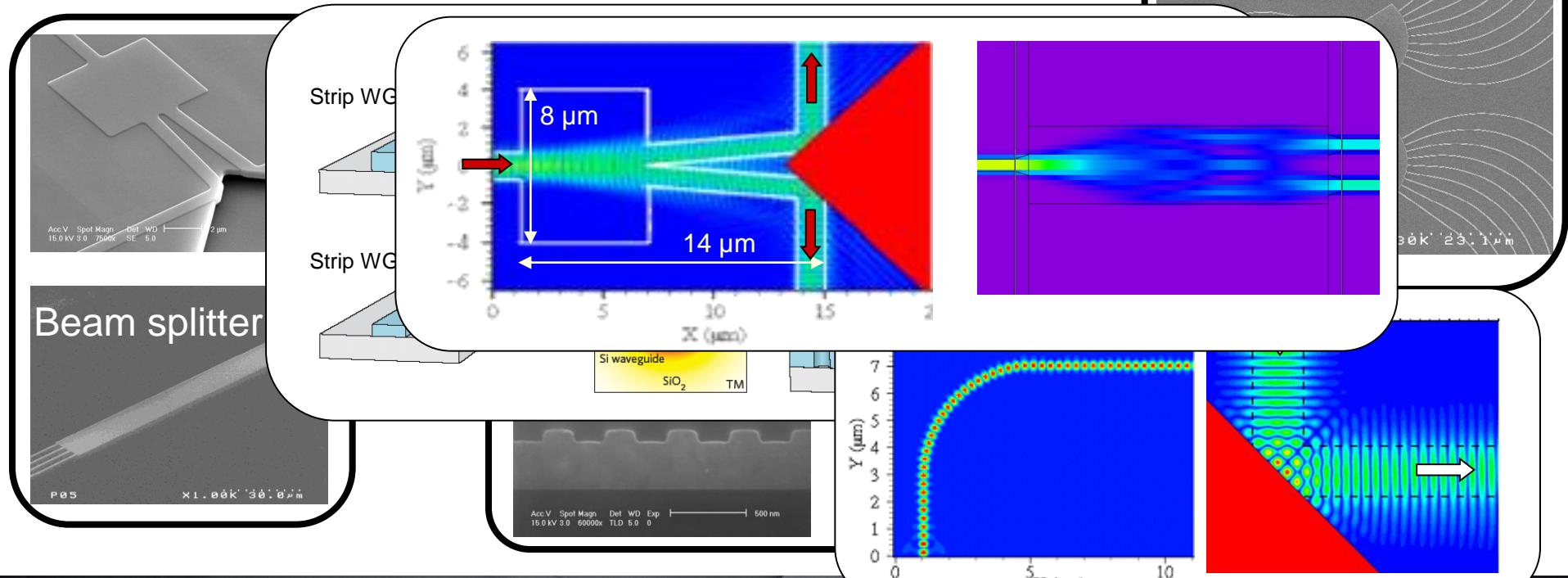
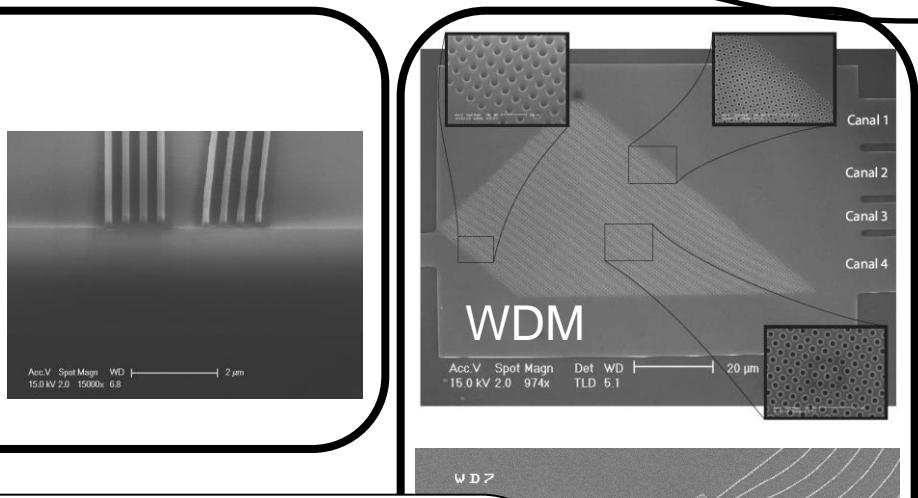
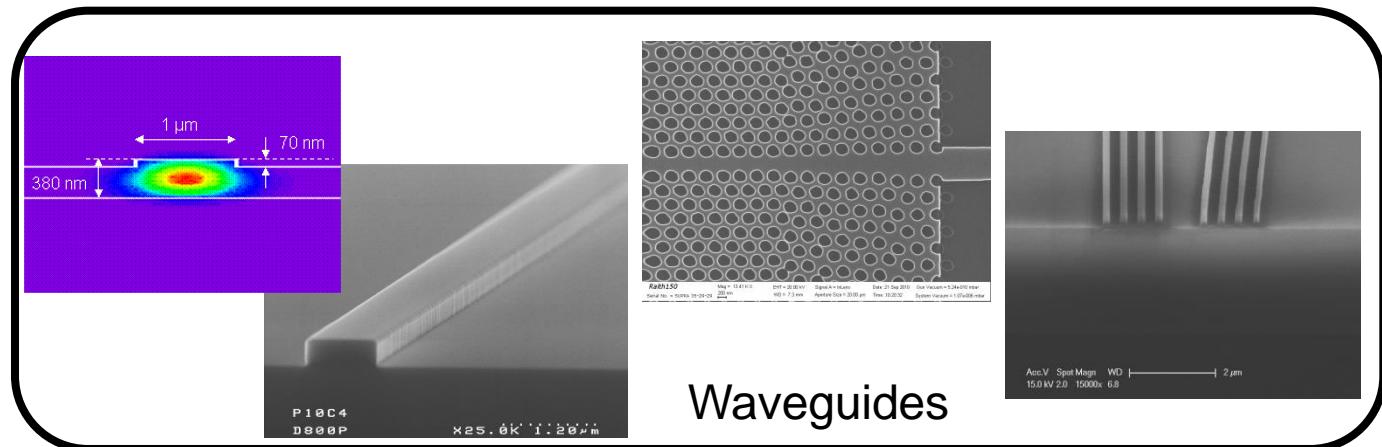
Contrast  $\sim 0.01 - 0.1$

Mode diameter  $\sim 8\mu\text{m}$

Bend radius  $\sim 5\text{mm}$

Size  $\sim 10 \text{ cm}^2$

Source: Slide from Wim Bogaerts – Summer school 2011 St Andrews

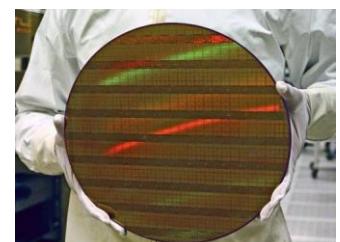
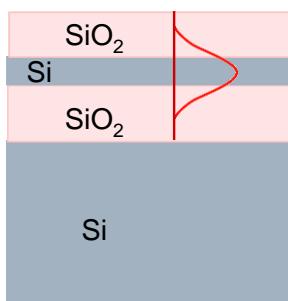




- Transparent in 1.3-1.6  $\mu\text{m}$  region
  - ✓ Low loss waveguides
- Take advantage of CMOS platform
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  - ✓ Strong light confinement
    - Small footprint (450nm x 220nm)



- Indirect bandgap material
  - ✓ No or weak electro-optic effect
  - ✓ “Lacks” efficient light emission
    - No Si laser
- No detection in 1.3-1.6  $\mu\text{m}$  region



## 1. Silicon photonics: motivation

## 2. Optoelectronic devices

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- Optical modulation
- Optical laser source

## 3. Electronic-photonic convergence

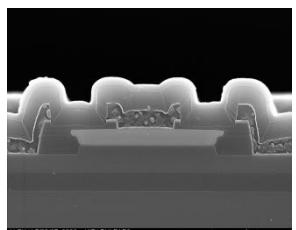
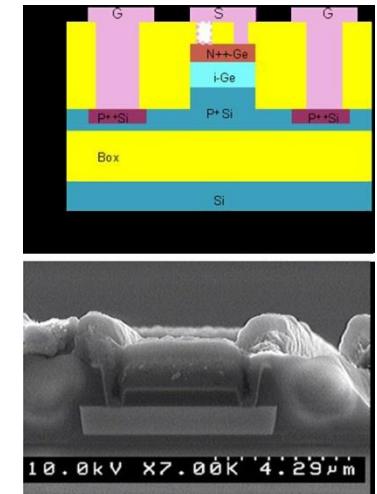
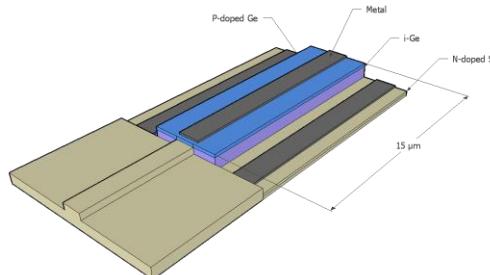
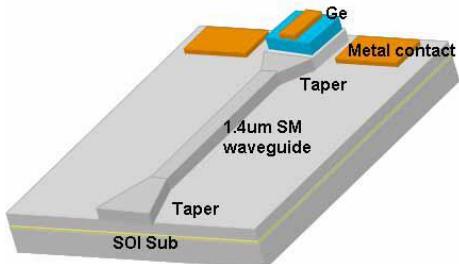
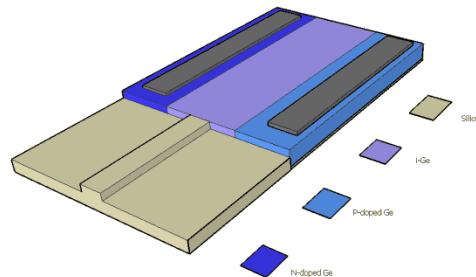
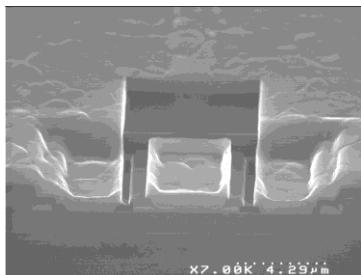
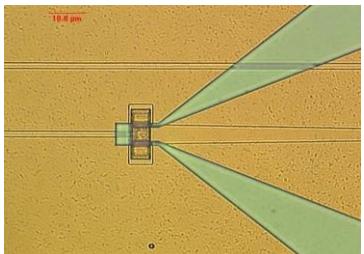
## 4. Conclusion



- Absorption coefficient of pure Ge
  - $\alpha \approx 9000 \text{ cm}^{-1}$  at  $\lambda = 1.3\mu\text{m}$   
 $\Rightarrow L_{\text{ABS}}^{95\%} \approx 3.3\mu\text{m} (!)$
  - $\Rightarrow$  Low capacitance devices
  - $\Rightarrow$  High frequency operation
- High carrier mobility



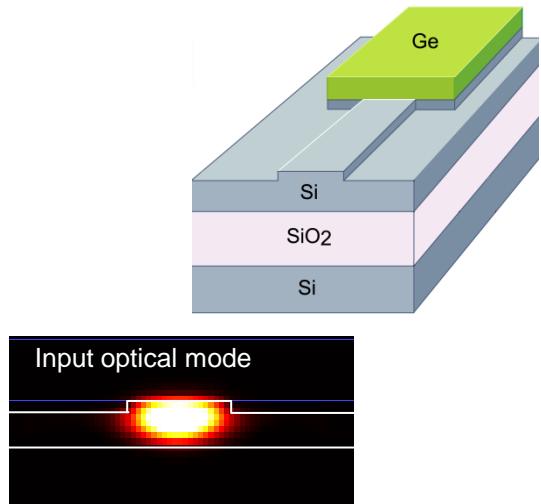
- Lattice misfit with Si of about 4.2%
  - $\Rightarrow$  specific growth strategies required (wafer-scale and localized)
- Low indirect bandgap:  $E_G = 0.66\text{eV}$ 
  - $\Rightarrow$  high dark current for MSM devices



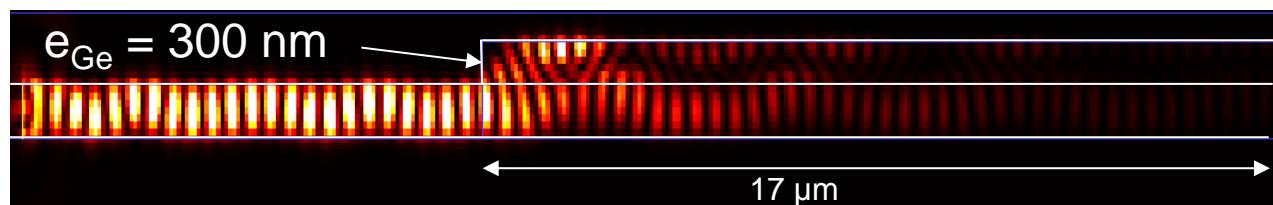
**Europe:** PSUD-IEF, CEA-Léti, Stuttgart Univ., Roma Univ. ...

**Asia:** Tokyo Univ., A\*Star, Petra, AIST, Chinese Academy of Sciences, ...

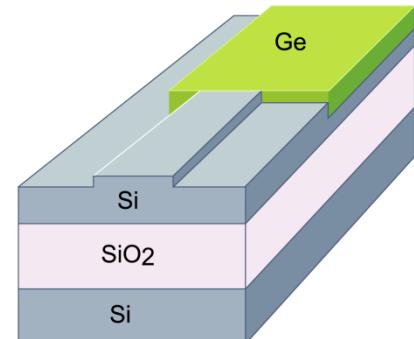
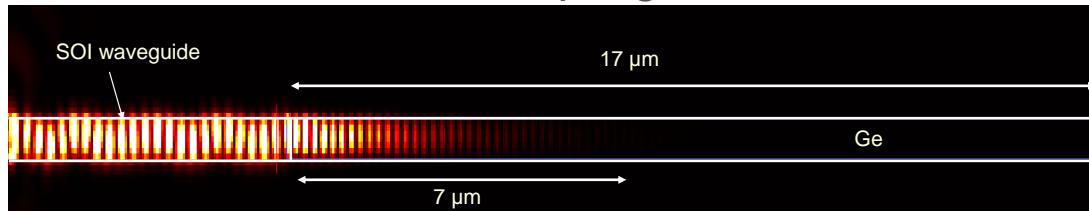
**North America:** Intel, MIT, IBM, Cornell, Luxtera, Lighthwire, Kortura, Oracle ...



Vertical coupling

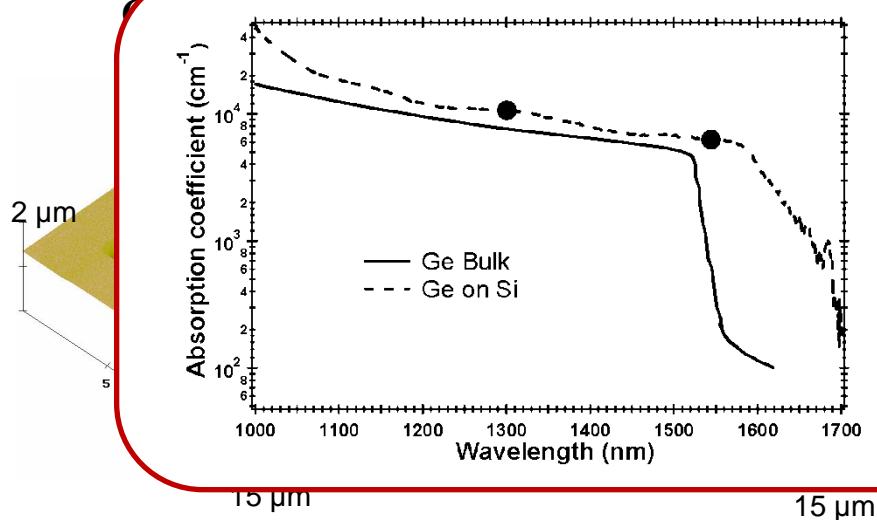


Butt coupling



- ⇒ Short absorption length => Low capacitance
- ⇒ Light absorption is independent of Ge film thickness

## Two PDCVD steps to overcome lattice mismatch issue

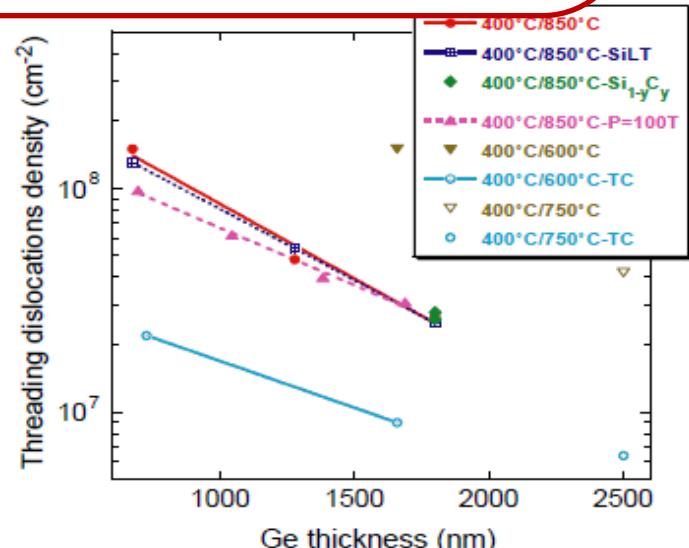


### Optical absorption

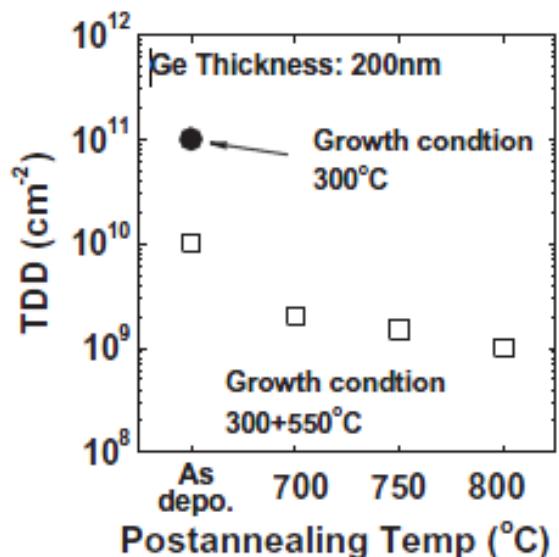
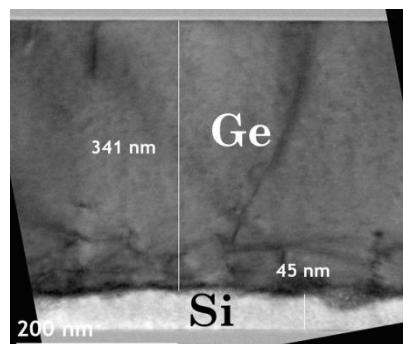
- ✓ Close to bulk values
- ✓ Bandgap shrinkage (50 nm)
  - Tensile strain
  - ⇒ Absorption up to 1.6 μm

## Overgrowth of Ge

- To avoid faceting inside the cavity
- To reduce Threading Dislocation Density (TDD)



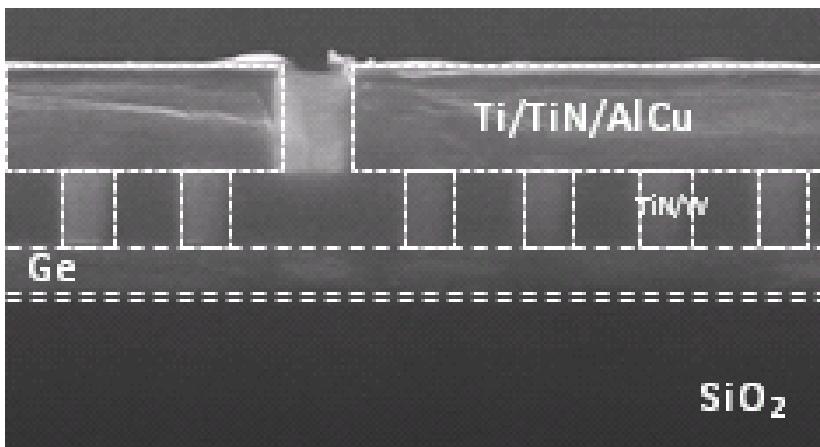
- Post epitaxial thermal cycling to further reduce TDD in the Ge layer
- CMP step to remove protruded Ge
- SiO<sub>2</sub> encapsulation
- Ion implantation of Ge
  - ✓ N-type : Phosphorus
  - ✓ P-type : Boron
- Rapid Thermal Anneal



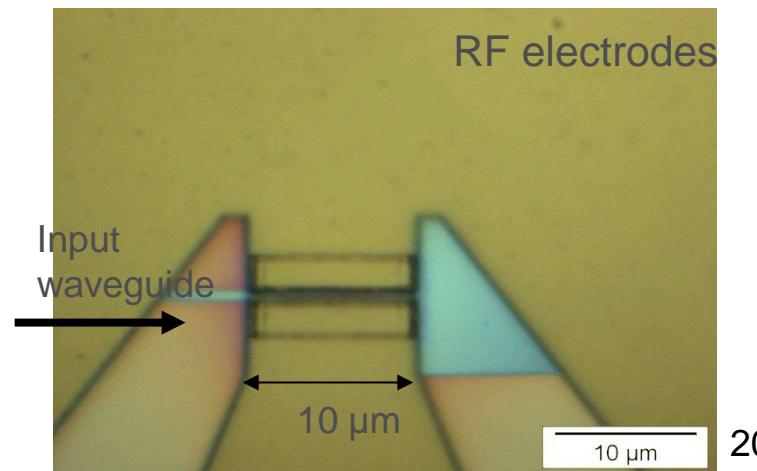
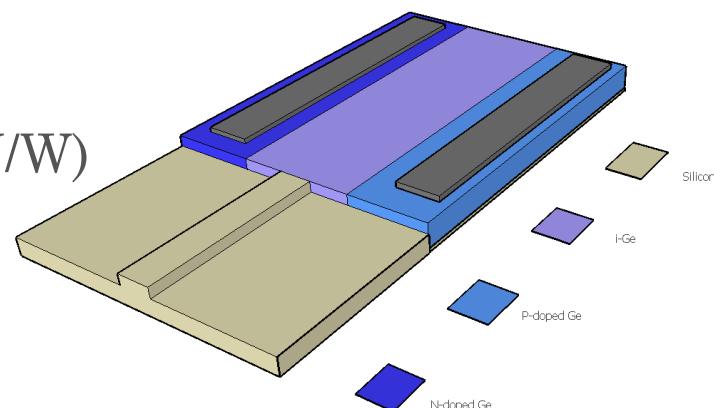
Y. Yamamoto et al., *Solid-State Electronics*, **60-1**, 2-6, (2011).

- Oxide encapsulation
- Planarization
- Contact definition

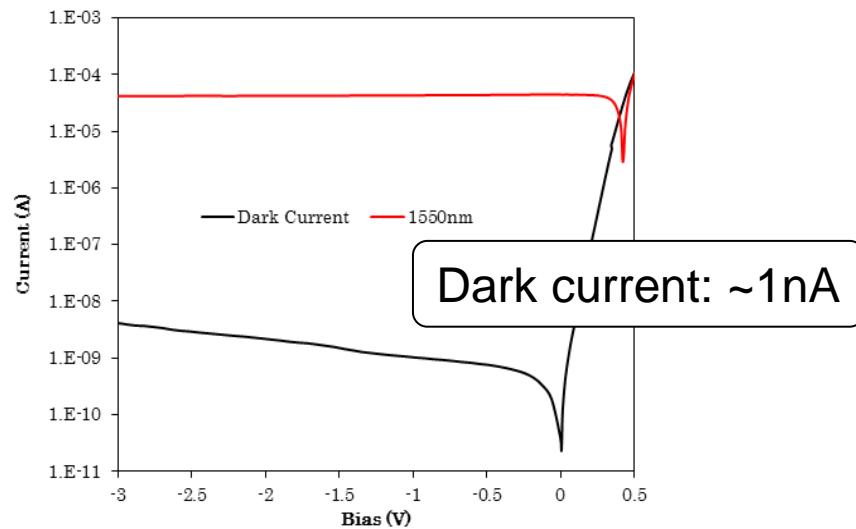
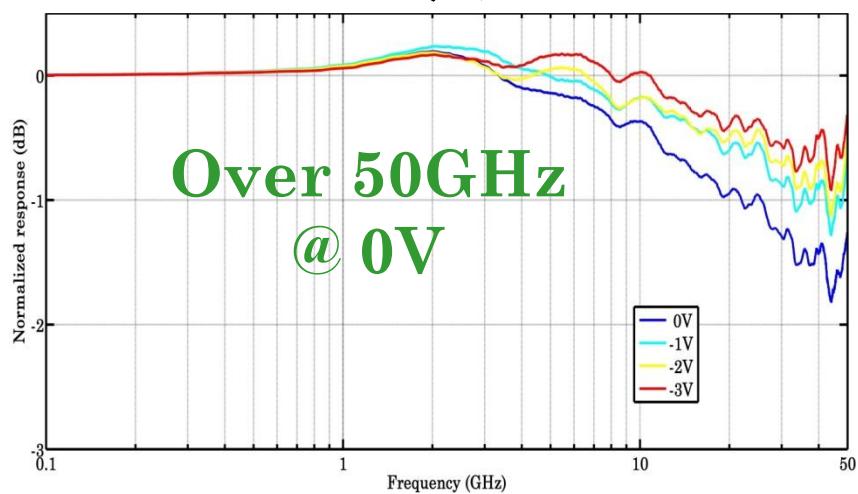
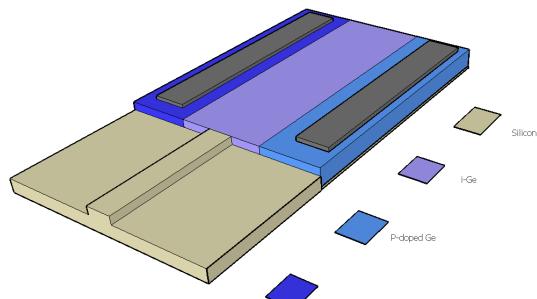
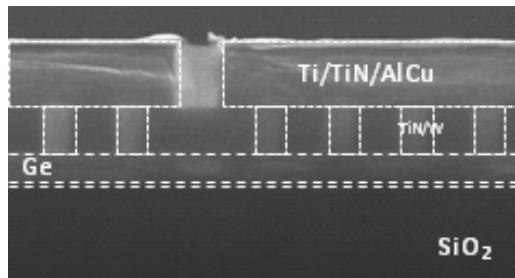
- 0.4x0.4 $\mu$ m vias for metal filling (TiN/W)
- Ti/TiN/AlCu pad defined by etching

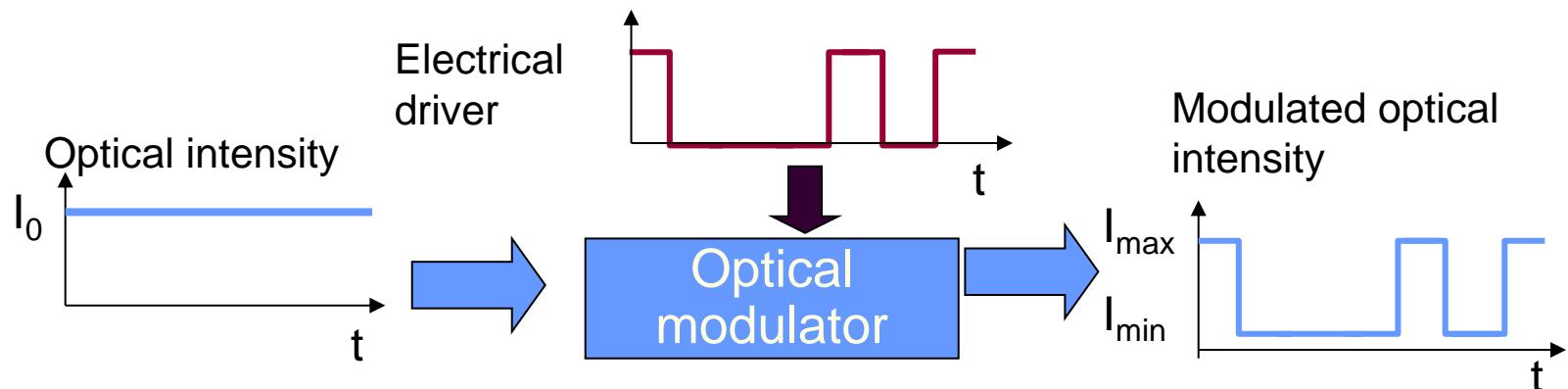


Lateral



20





Electro-absorption

Absorption coefficient variation  
with electric field

**Intensity modulation**

Electro-refraction

Refractive index variation with  
electric field

**Phase modulation**

## Nonlinear Polarization:

$$\tilde{P}(t) = \chi^{(1)} \tilde{E}(t) + \cancel{\chi^{(2)} \tilde{E}^2(t)} - \chi^{(3)} \tilde{E}^3(t) + \dots$$

✓ **Pockels effect:**

- Linear electro-

## ✓ Wavelength conversion

- Second Harmonic Generation (SHG)

*Silicon is a centro-symmetric material !*

✓ **Kerr effect:**

- Nonlinear electro-

## ✓ Wavelength conversion

- Four wave mixing (FWM)

$$n = n_0 + I * n_2$$

$$n_2^{Si} \sim 10^{-14} \text{ cm}^2 / \text{W}$$

&gt;&gt;

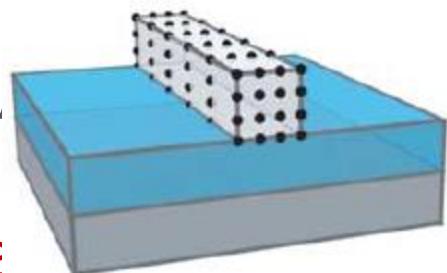
$$n_2^{glass} \sim 10^{-16} \text{ cm}^2 / \text{W}$$

## Nonlinear Polarization:

$$\tilde{P}(t) = \chi^{(1)} \tilde{E}(t) + \cancel{\chi^{(2)} \tilde{E}^2(t)} - \chi^{(3)} \tilde{E}^3(t) + \dots$$

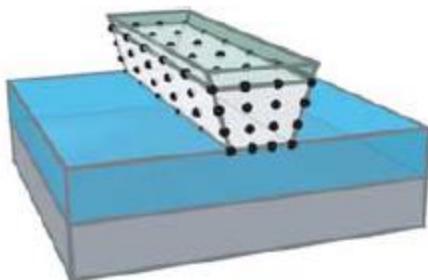
✓ Pockels effect:  
layer

➤ Linear electro-



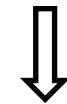
With straining  
layer

effect



G)

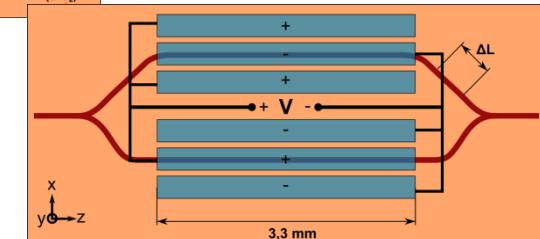
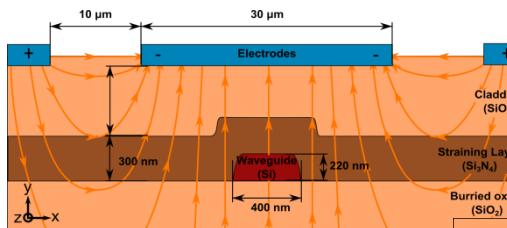
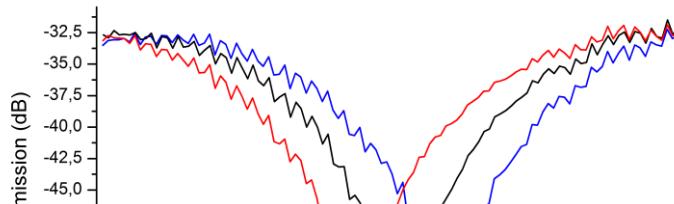
Break the symmetry  
of silicon crystal



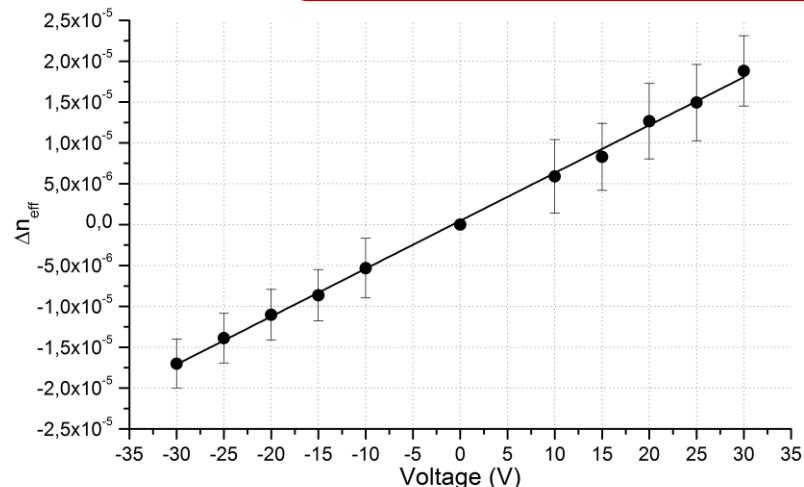
Strained silicon  
photonics

## Pockel's effect:

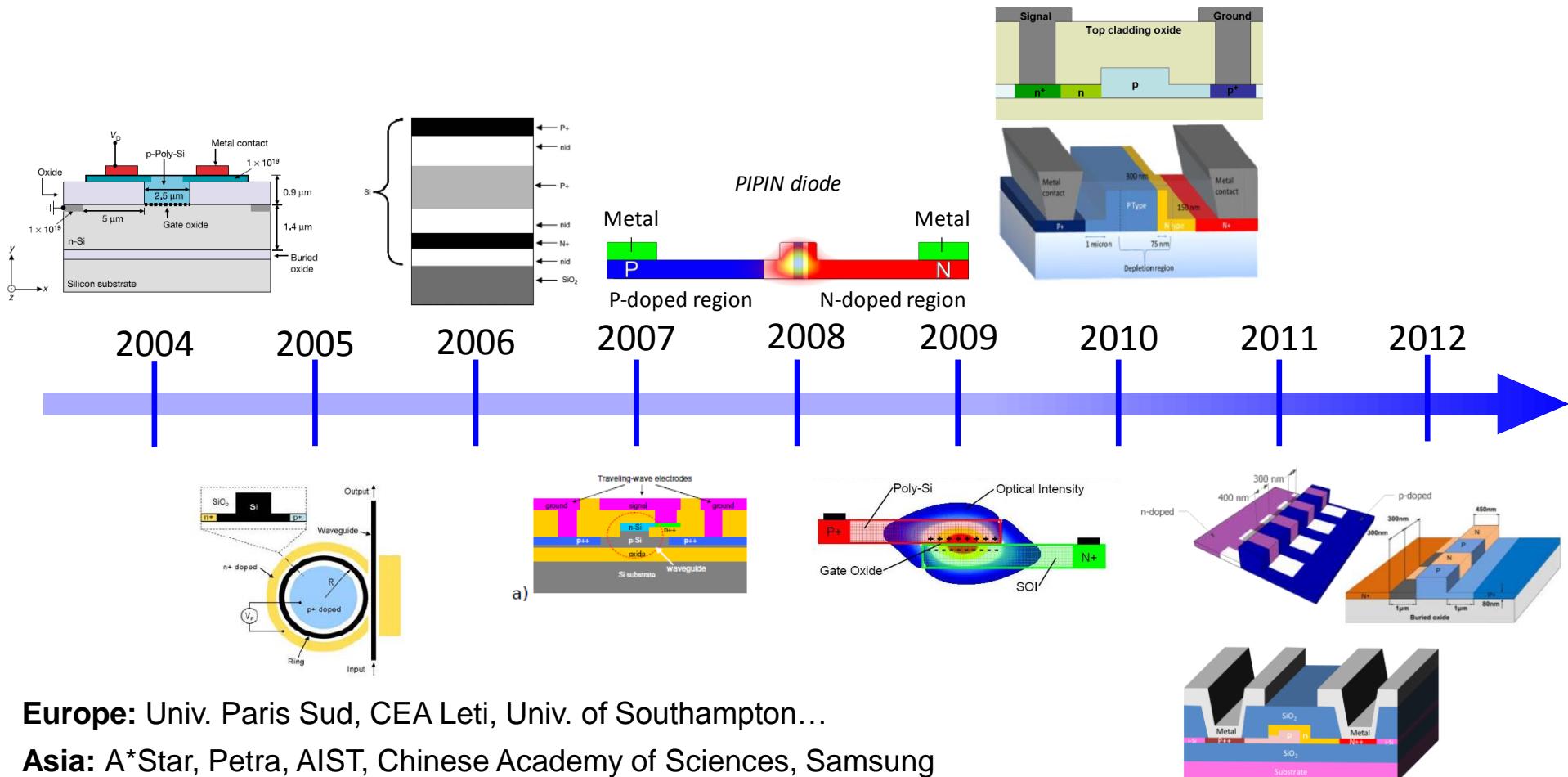
$$n_{eff}(30 \text{ V}) = (1.9 \pm 4) \times 10^{-5}$$



Still weak effect and high voltage BUT promising  
for the development of low power consumption devices



- ✓ Intrinsically high speed
- ✓ Field effect – no capacitance
  - Low power consumption
- ✓ Low bias swing
- ✓ Low insertion loss
  - No doped regions



**Europe:** Univ. Paris Sud, CEA Leti, Univ. of Southampton...

**Asia:** A\*Star, Petra, AIST, Chinese Academy of Sciences, Samsung Electronics, Tokyo Institute of Technology ...

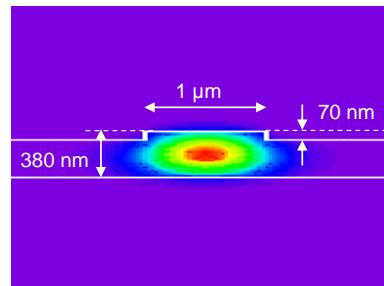
**North America:** Intel, IBM, Cornell, Luxtera, Lighwire, Kotura, Oracle ...

# Electro-refraction vs intensity variation

Electro-refraction effect:

- ✓ carrier density variation: accumulation, depletion, injection

ASR Passif



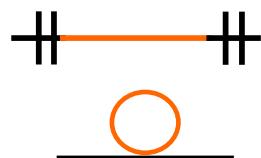
Refractive index variation



Effective index variation of the guided optical mode



Interferometers



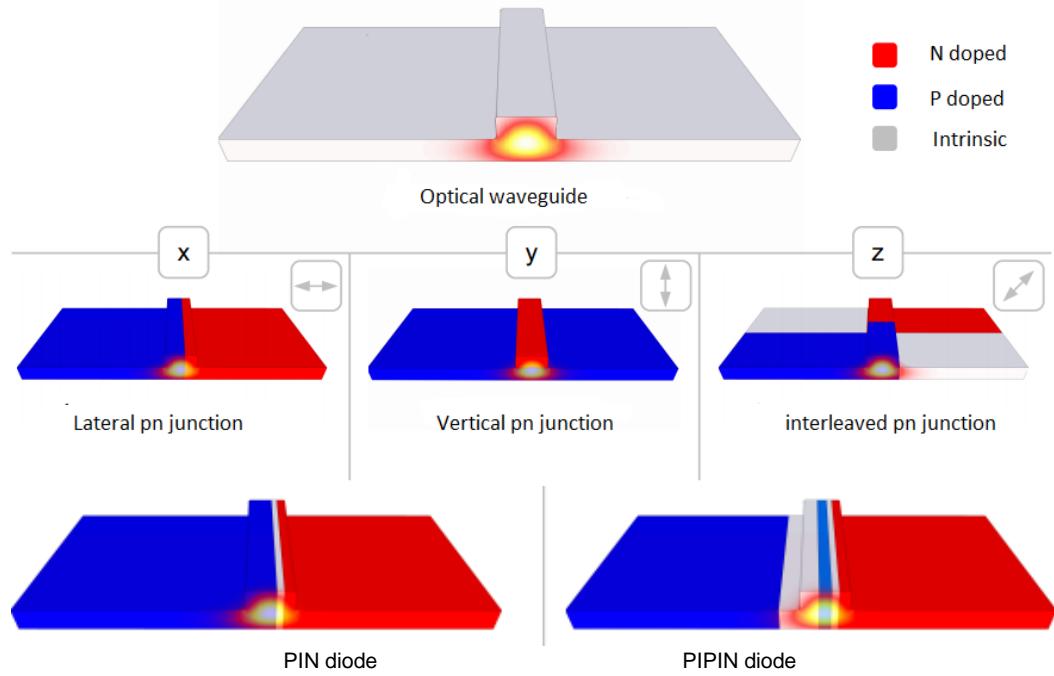
Phase variation



Optical intensity variation

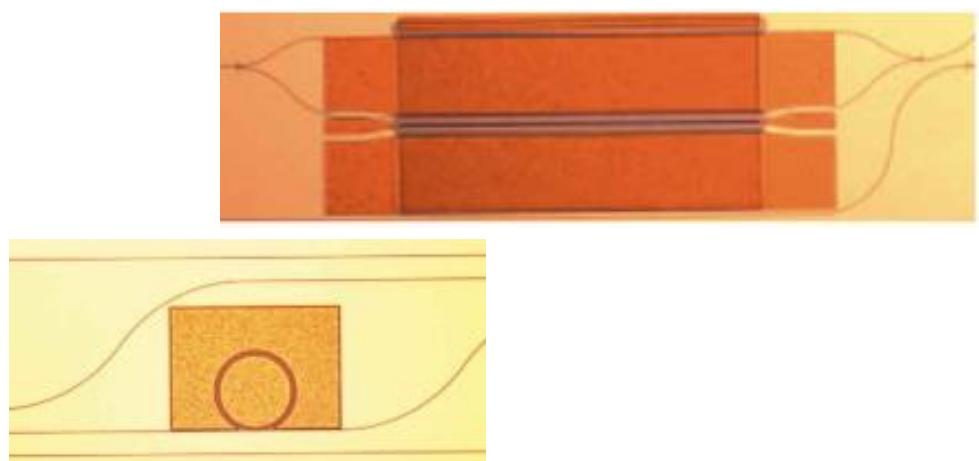
## □ Phase shifters:

- PN diode
- Interleaved PN diode
- PIN diode
- PIPIN diode
- MOS capacitor



## □ Interferometers

- Ring resonator
- Mach-Zehnder
- Photonic crystals



## Example: carrier depletion in interleaved pn diode

Free carrier concentration

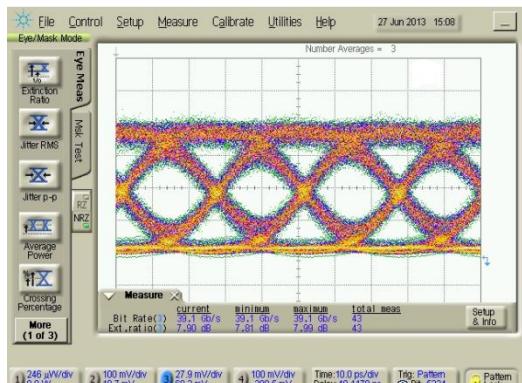
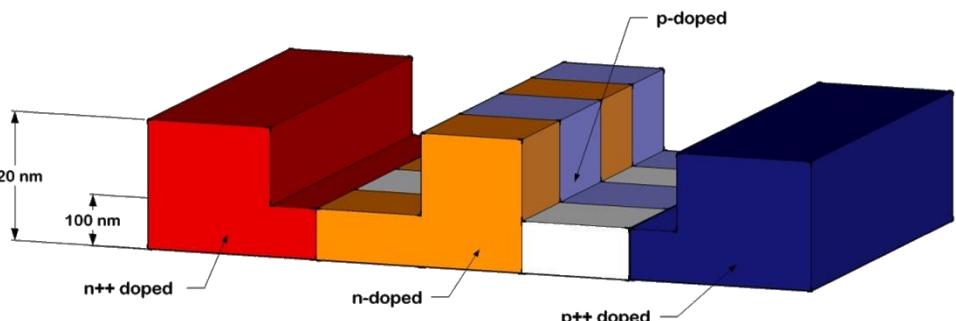
n-doped

Light propagation

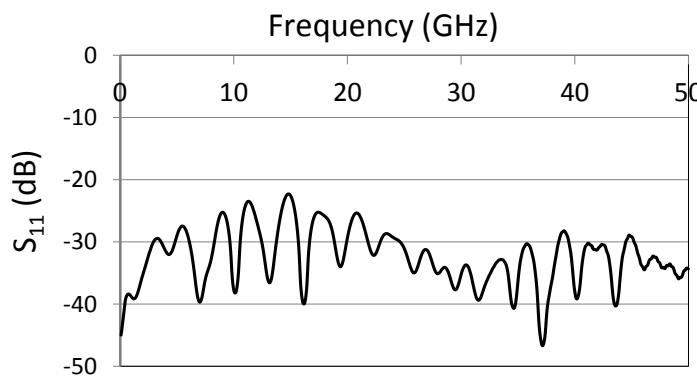
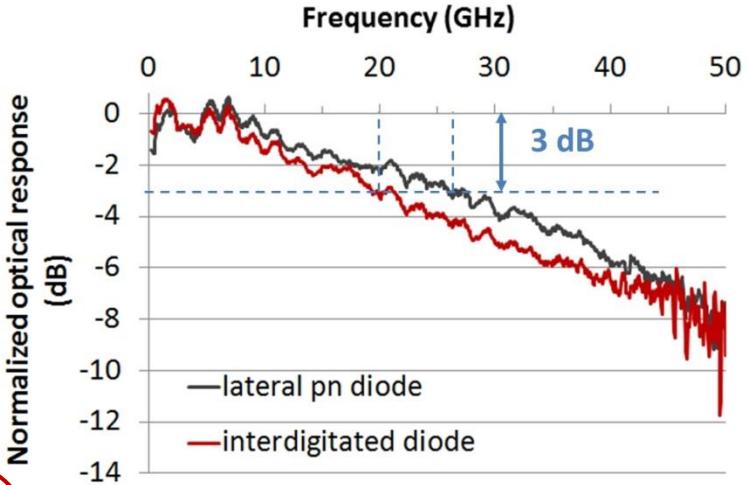
### Figures of merit

- $V_\pi L_\pi$  Modulation efficiency
- IL Insertion loss
- $f_c$  -3dB bandwidth
- ER Extinction ratio
  
- Voltage swing
- Power consumption

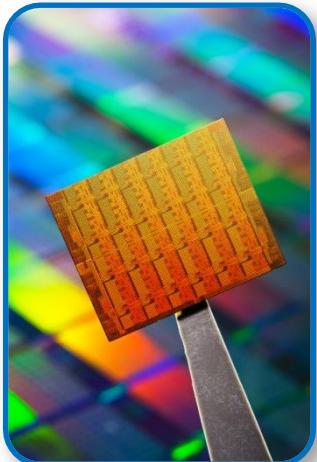
Geometry: 0,95mm long Mach-Zehnder modulator



- ✓  $V_{\pi} L_{\pi} \sim 2.2 \text{ V.cm}$
- ✓ Extinction ratio: 8 dB
- ✓ Insertion loss: 4 dB
- ✓ Frequency > 20 GHz
- ✓  $S_{11} < 20 \text{ dB}$
- ✓ Data rate: 40 Gbit/s



## Short distance and high volume applications (electrical bottleneck)



Optical  
interconnects



Data-center

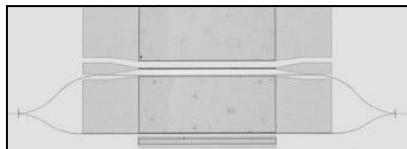
### Main challenges:

- ✓ Driving voltage of modulator
- ✓ Compactness
- ✓ Power consumption

### ITRS Roadmap: Optical interconnect

- (...) A large variety of CMOS compatible modulators have been proposed in the literature (...)
- “The primary challenges for optical interconnects at the present time are producing cost effective, low power components.”

Mach Zehnder modulators  
 $\sim 3 \text{ pJ/bit}$

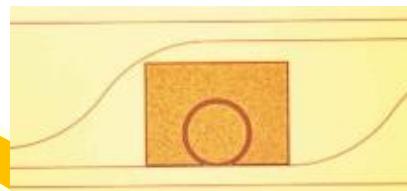


For emitters and short optical links:

$\sim 100 \text{ fJ/bit}$  down to  $\text{fJ/bit}$

(D.A.B. Miller, Opt Exp. , 2012)

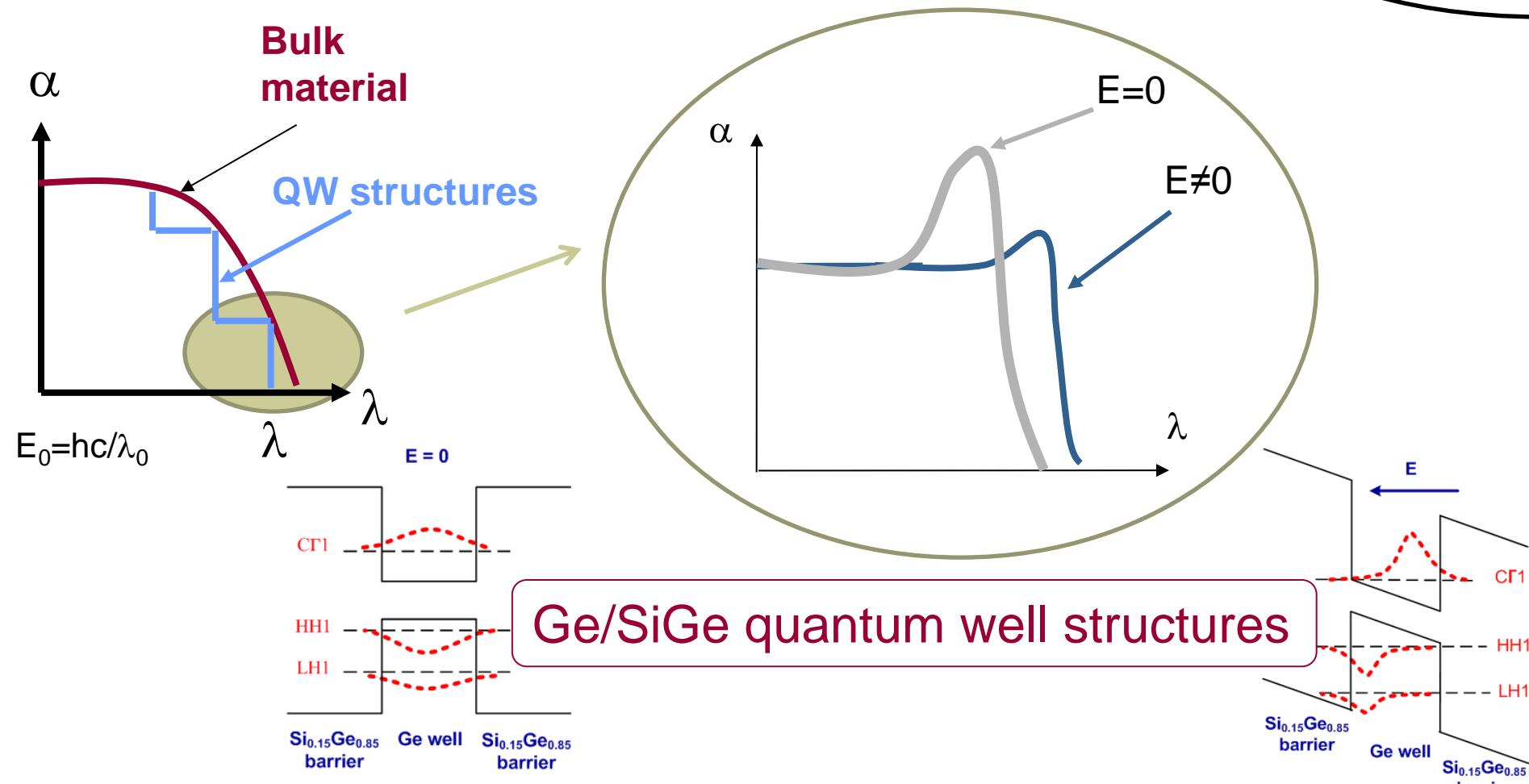
Ring resonator modulators  
 $\sim 0.5 \text{ to } 1 \text{ pJ/bit}$



- Franz-Keldysh effect  
in bulk material
- Quantum Confined Stark Effect  
in quantum well

Electro-absorption



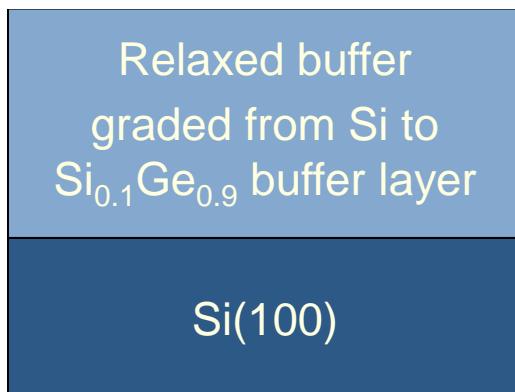


- Absorption edge in QW structures is more abrupt than in bulk material
- $E_0$  depends on the quantum well thickness
  - Adjustment of the wavelength is possible

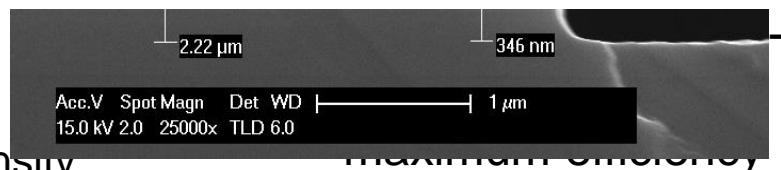
- ✓ Growth of Ge/SiGe multiple quantum wells

## LEPECVD

Low energy plasma enhanced chemical vapor deposition



Low dislocation density  
- Best device performance



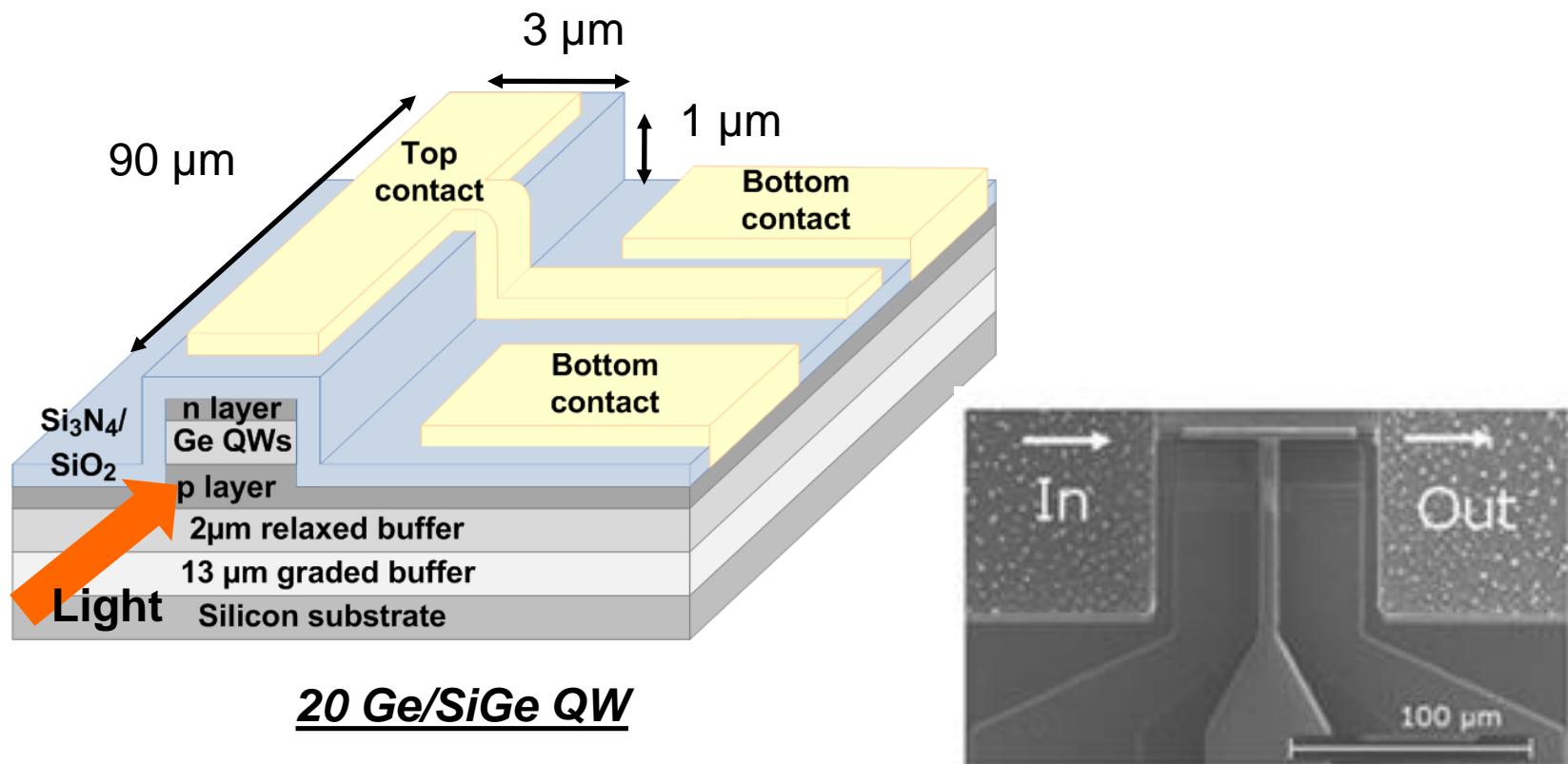
maximum efficiency

- ✓ Temperatures down to 400°C

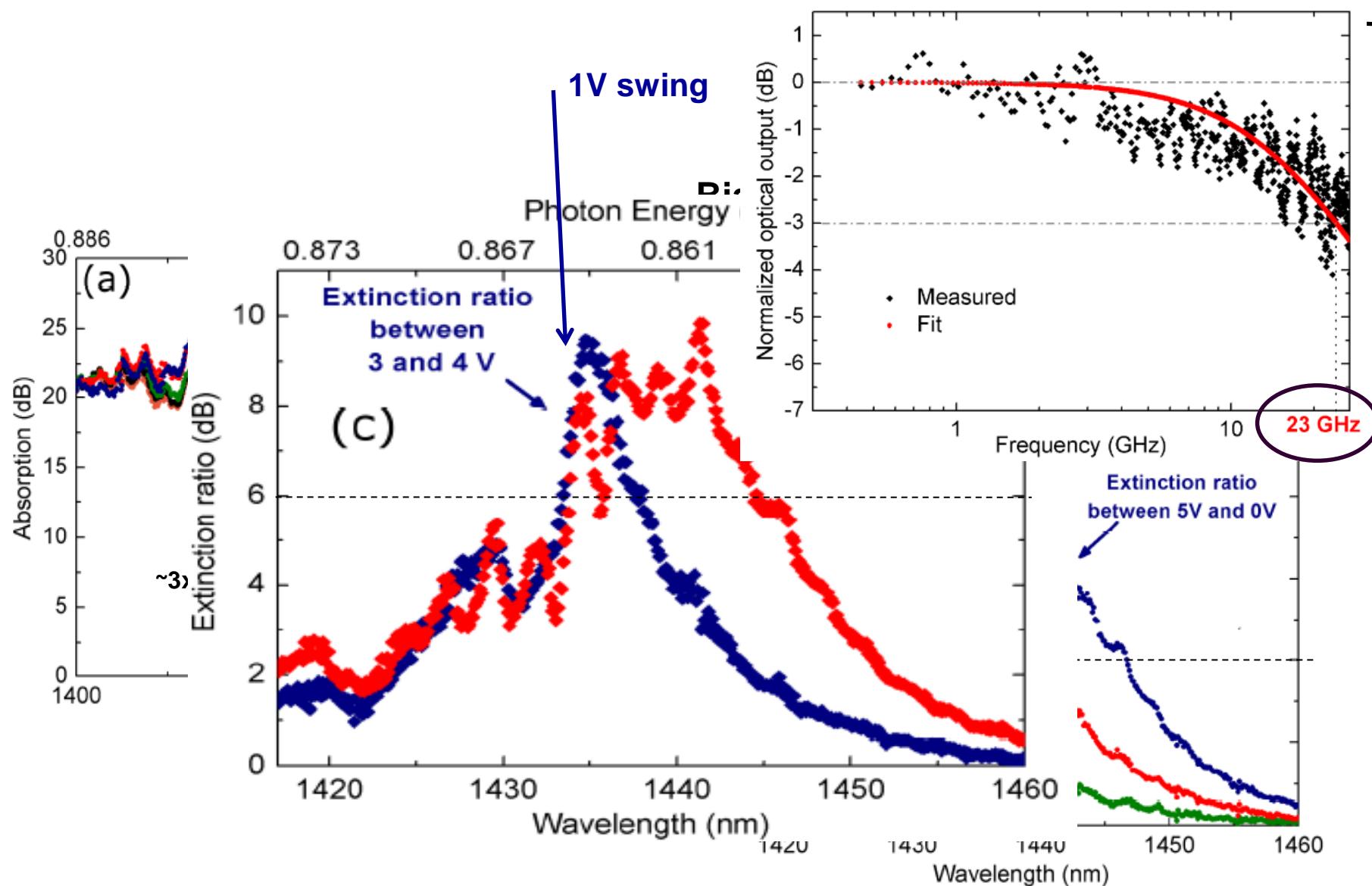
L-NESS  
Como, Italy



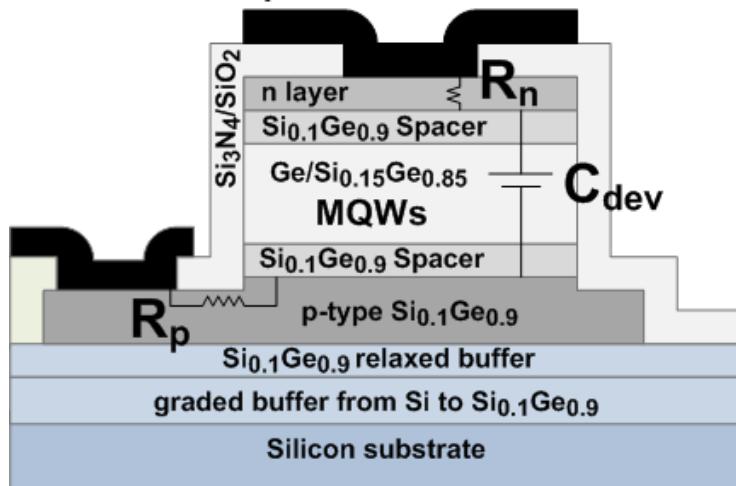
L-NESS



P. Chaisakul et al., Optics Express (2012).



$$R_s = R_n + R_p$$



Energy to charge the device

$$\text{Energy/bit} = 1/4 (CV_{pp})^2$$

Energy dissipation of photocurrent

$$\text{Energy/bit} = 1/B (I_{ph}V_{bias})$$

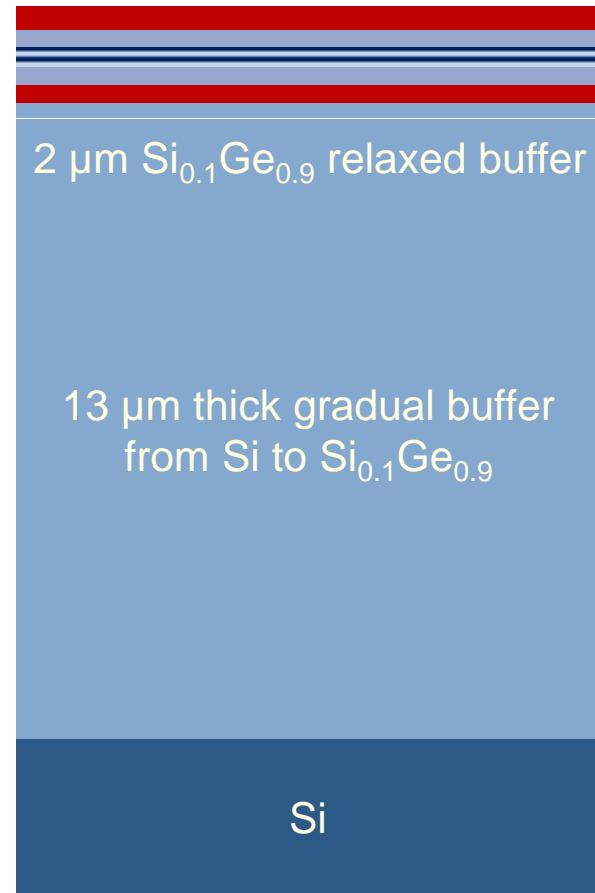
$$C \sim 62 \text{ fF} \rightarrow \text{Energy/bit} = \underline{\underline{70 \text{ fJ/bit}}}$$

(for a voltage swing of 1 V, 20 Gbps, 0.5 mW input power)

# Integrated circuits based on Ge/SiGe QW ?



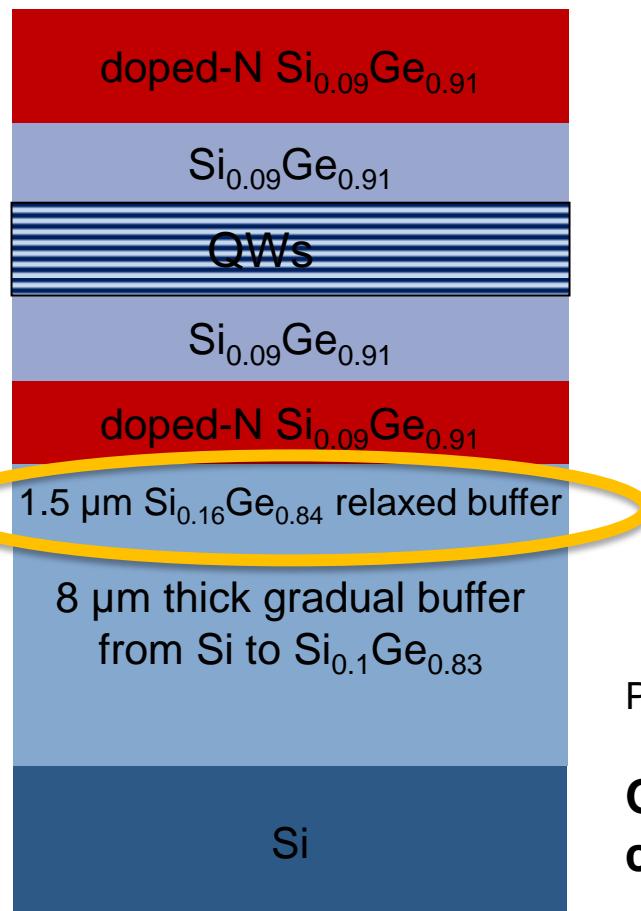
Schematic description



The real scale

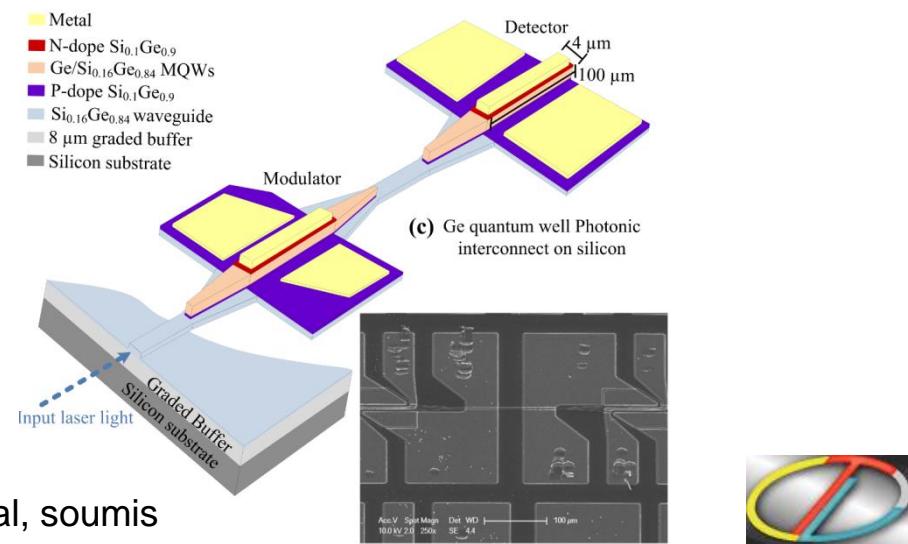
**Challenge: coupling the light from silicon to Ge/SiGe QW**

## 1<sup>st</sup> option: waveguide in the relaxed SiGe layer (thanks to the graded buffer )



Ge concentration in the waveguide: trade-off between

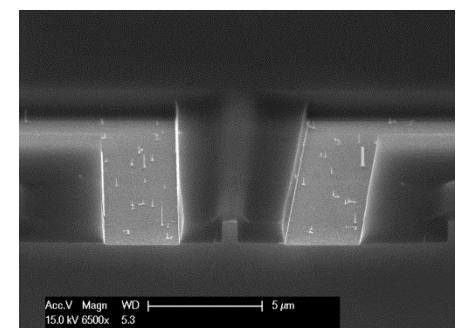
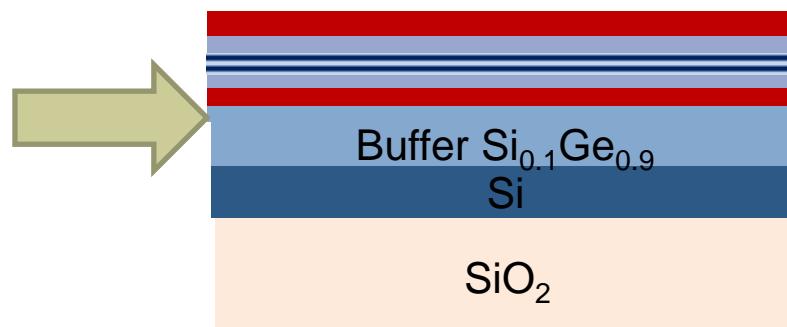
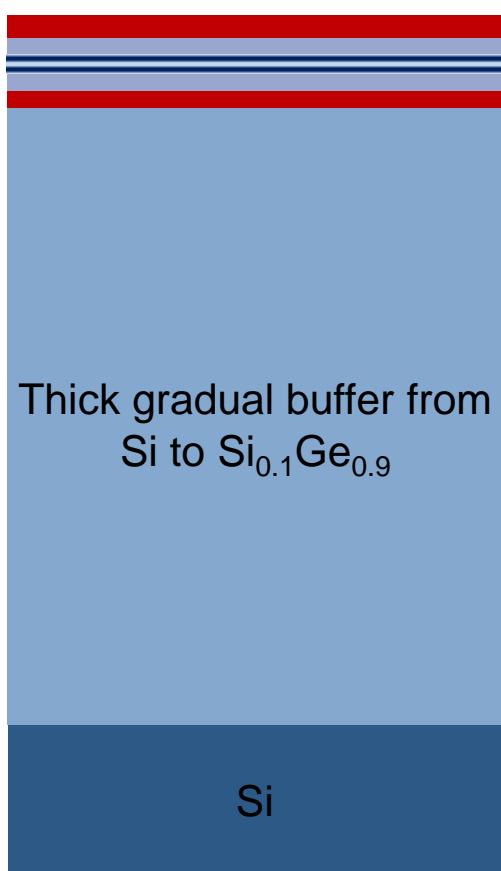
- Strain compensation
- Optical loss



**Optical loss of each device, including input/output coupling with  $\text{Si}_{0.16}\text{Ge}_{0.84}$  waveguide < 5dB**

## **2<sup>nd</sup> option: decrease the thickness of the buffer layer**

Challenge: keeping homogeneous and high quality layers



**Ge/SiGe modulator integrated with SOI : estimated performance :**  
Extinction ratio = 7.7 dB, loss = 4 dB

M-S. Rouifed et al, soumis

**Under fabrication**



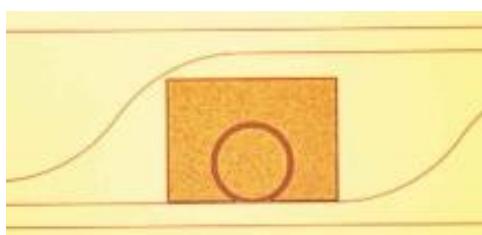
## Carrier depletion modulator MZi

Energy/bit  $\sim 5 \text{ pJ/bit}$

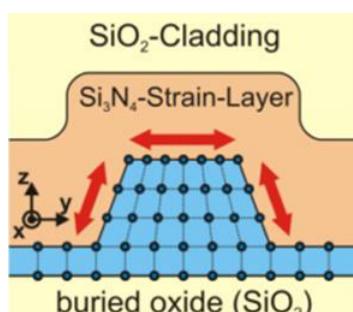


## Ring resonator modulator

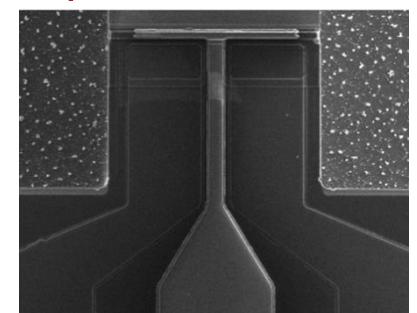
Energy/bit  $\sim 0.7 \text{ pJ/bit}$



## Strained modulator

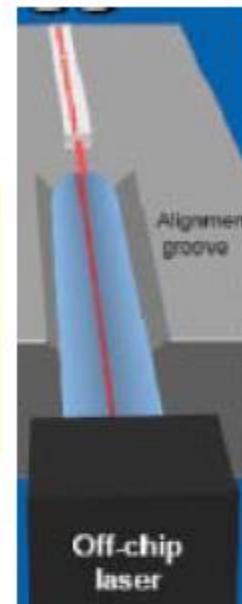


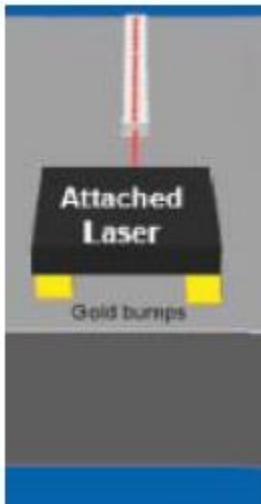
## EA Ge/SiGe modulator energy/bit $\sim 0.07 \text{ pJ/bit}$



## Ultra low power consumption modulator energy/bit $\sim \text{few fJ/bit}$

**Off-chip laser**  
Fiber attachment & alignment  
**High coupling losses**  
Very expensive  
Non-integrated



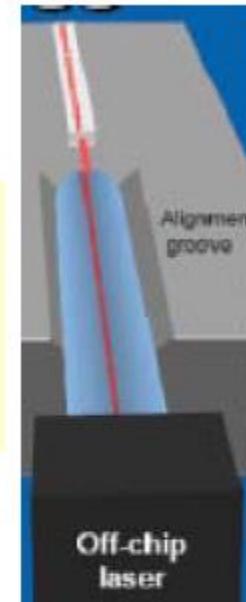


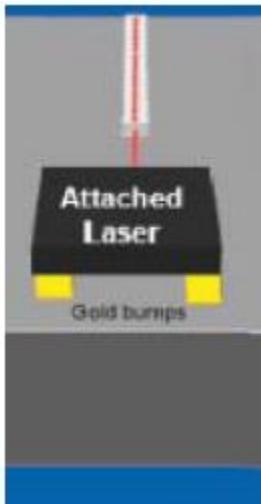
### Attached laser

Tight alignment tolerances  
Gold metal bonding  
Expensive

### Off-chip laser

Fiber attachment & alignment  
High coupling losses  
Very expensive  
Non-integrated



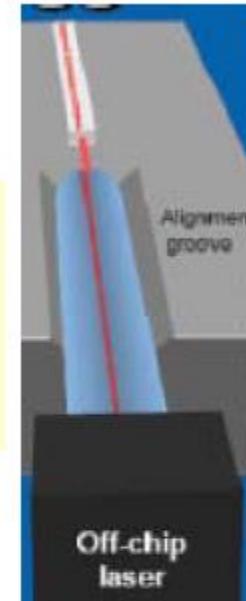


### Attached laser

Tight alignment tolerances  
Gold metal bonding  
Expensive

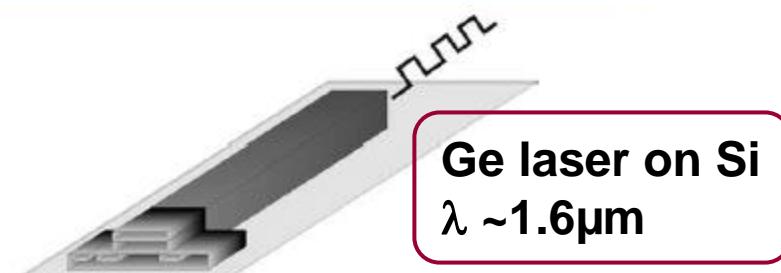
### Off-chip laser

Fiber attachment & alignment  
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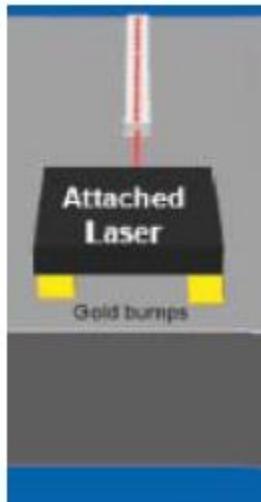


### Monolithic laser Si compatible

Not any alignments  
Highly integrable  
Low cost  
Electronic-photonic integration



courtesy: Blas Garrido

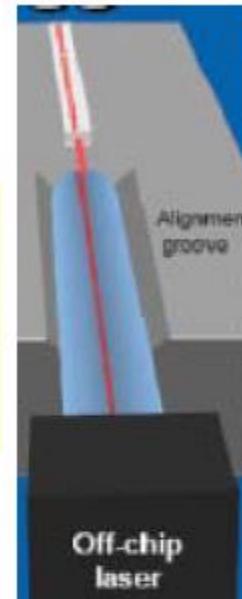


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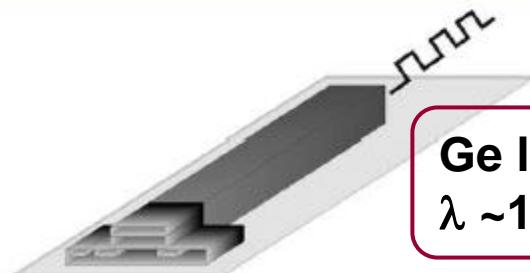


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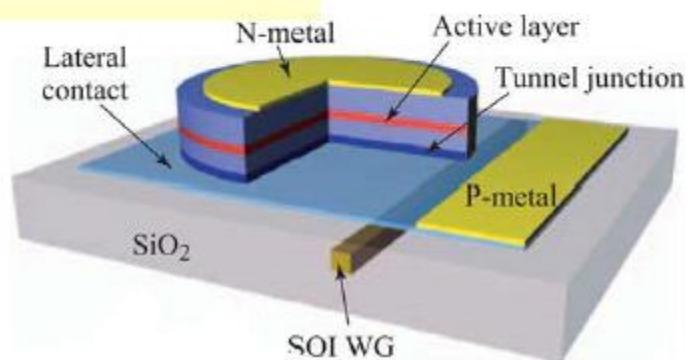
### Hybrid integrated laser

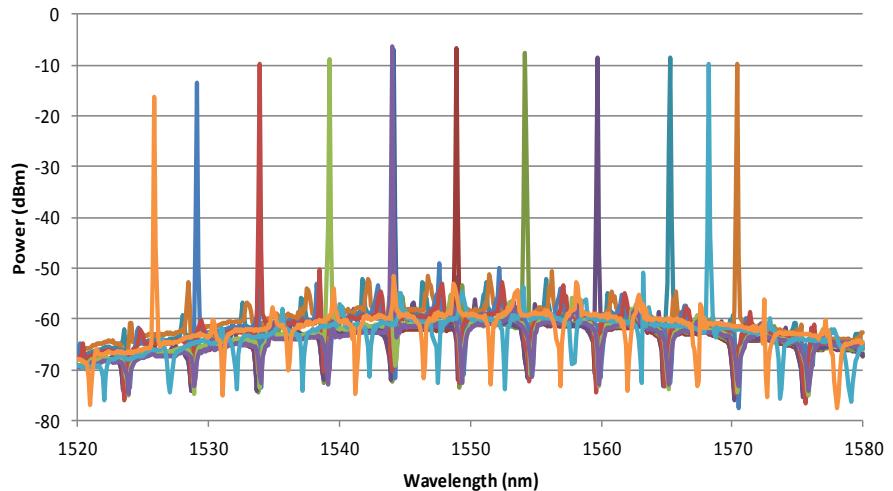
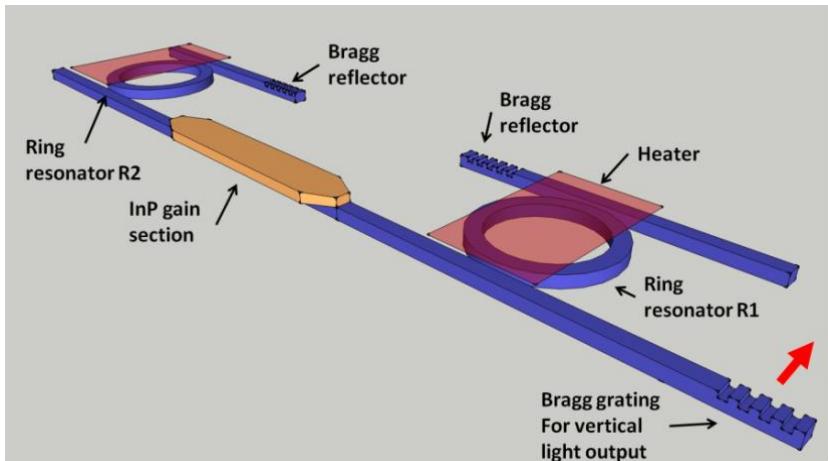
InP bonded laser to SOI CMOS  
No alignment  
Possibly to integrate  
Moderate cost



**Ge laser on Si**  
 $\lambda \sim 1.6\mu\text{m}$

courtesy: Blas Garrido





- 20 mA threshold at room temperature
- >45dB SMSR, tuning range 45nm

III-V lab

courtesy: G.H. Duan

## 1. Silicon photonics: motivation

## 2. Optoelectronic devices:

- Photodetection
- Optical modulation
- Optical laser source

## 3. Electronic-photonic convergence

## 4. Conclusion

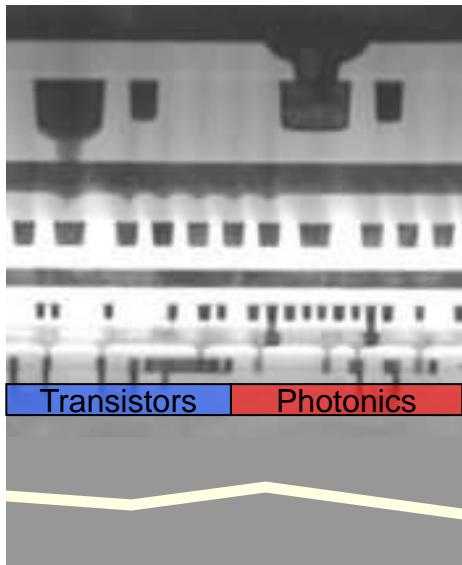
- Use wire-bonding to connect chips



Not a waferscale approach

Not compatible with micro-electronics packaging





## Front-end fabrication

- 😊 Very low parasitics
- 😢 Custom SOI, specific libraries
- 😢 process co-integration

# CMOS Photonics Process: LUX-G

- **LUX-G CMOS Process:**

- 130 nm CMOS SOI Technology Platform (8") based on Freescale Semiconductor's HIP7SOI (PowerPC™ microprocessors and controllers)
- Extensive library of photonic and electronic devices (including high-speed transistor models).

- **"Photonic-enabled" CMOS SOI process:**

- Shallow trench etch: definition of waveguides and grating couplers
- Selective Ge epitaxy for photo-detector integration
  - Low temperature growth of relaxed Ge films
  - Standard CMOS foundry toolset for Ge epitaxy (SiGe stressors, HBT)
- After-salicidation approach:
  - No need for transistor protection
  - One contact module for all devices

- **LUX-G CMOS Process in manufacturing mode since 2008 (Maturity Level 3 at Freescale Semiconductor):**

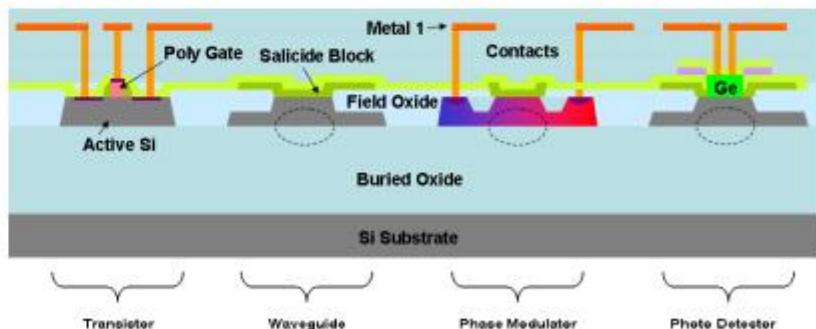
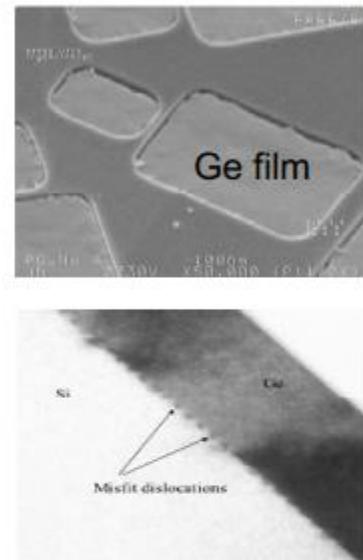
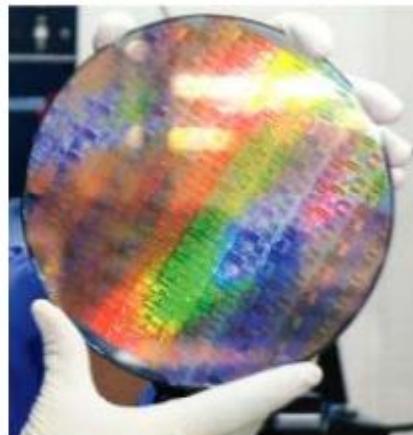
- All processes and tools standard and fully compatible with full flow SOI CMOS
- Under change control and run by production team
- Second of a kind (SOAK) fab tools verified in split lots
- Process windowing experiments on split lots completed satisfactory
- More than 1500 wafers (~ 61 lots) processed

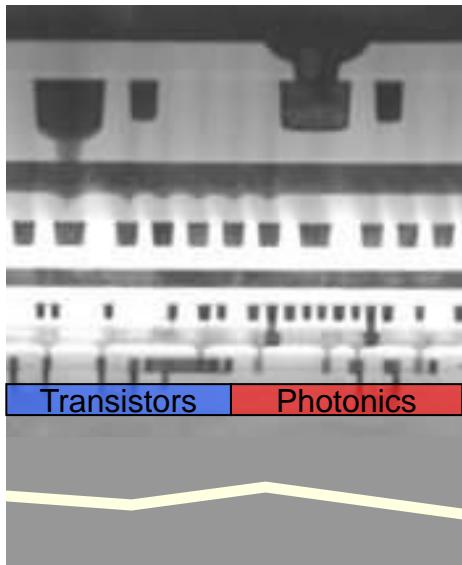
- **Electronic and photonic device models:**

- Based on material from different lots and process skews
- Accurate transistor and interconnect models established
- Results in improved circuit designs (e.g. power reduction) and high yields

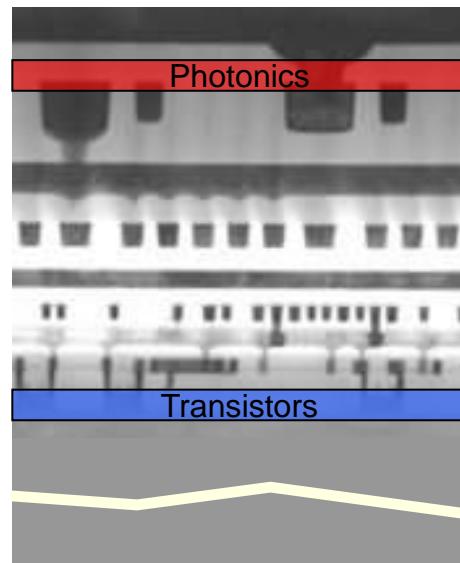
- **Passed industry standard reliability qualification (JEDEC)**

- Hot Carrier Injection, Negative Bias Thermal Instability, Time Dependent Dielectric Breakdown, Electromigration
- Performed on nmos, pmos, sgo and dgo test structures from 3 different lots





**Front-end fabrication**



**Back-end fabrication**

- 😊 Very low parasitics
- 😢 Custom SOI, specific libraries
- 😢 process co-integration

- 😊 On top of CMOS or in metal layers
- 😊 Serial process
- 😢 Compound yield
- 😢 Thermal budget < 400C

# MIT BEOL approach

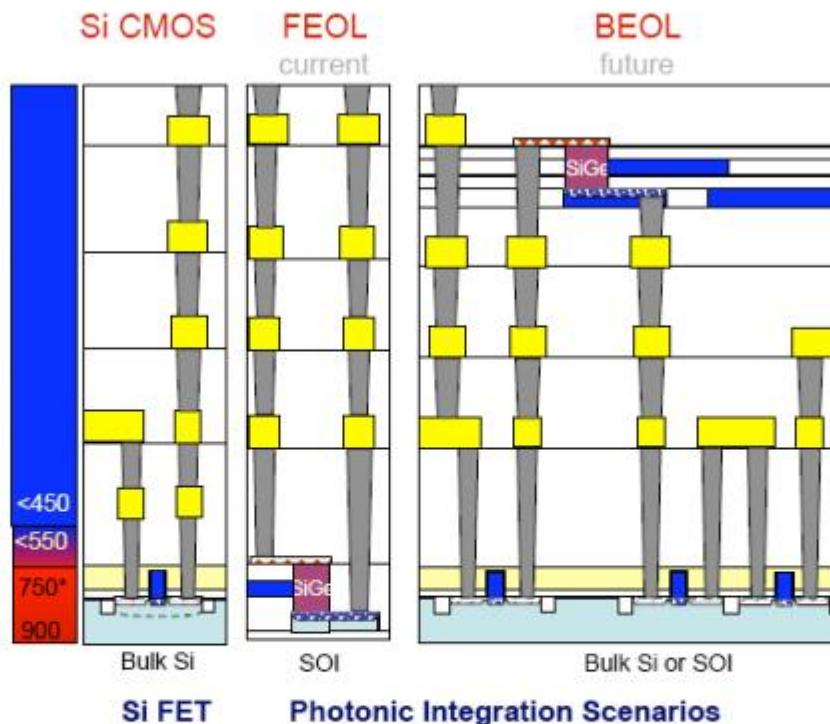
## Target Areas for Integration

### FEOL for current devices

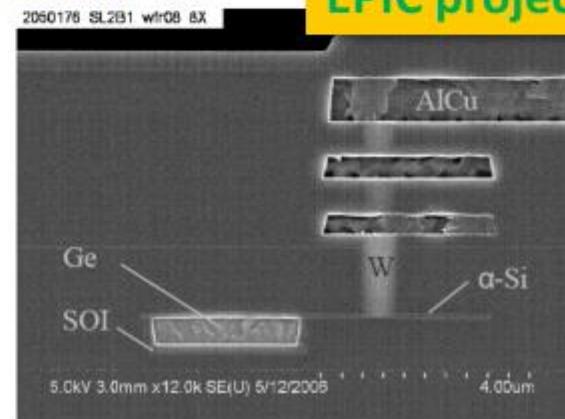
- Shared area with FET's
- Crystalline Si low loss WG's
- Temperature tolerant processing

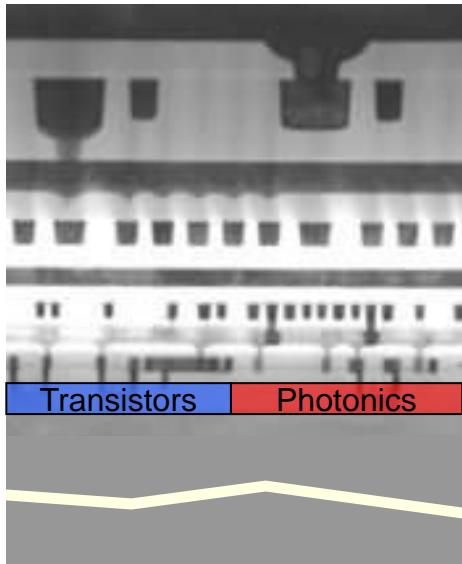
### BEOL for future device generations

- $T_{\text{limit}} < 450 \text{ }^{\circ}\text{C}$
- Current research focus



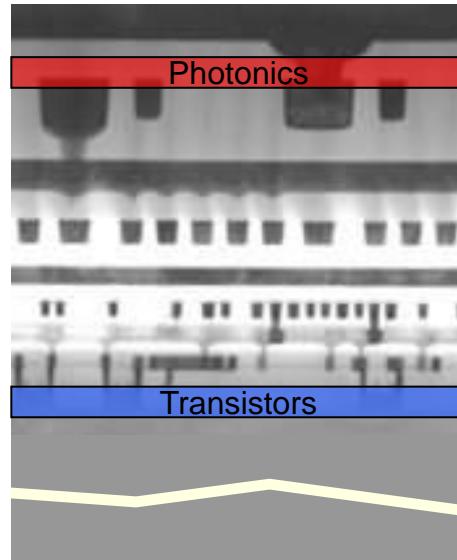
EPIC project





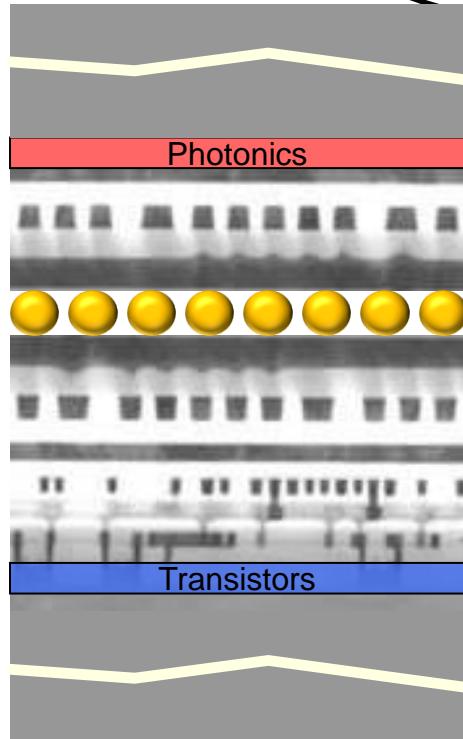
## Front-end fabrication

- 😊 Very low parasitics
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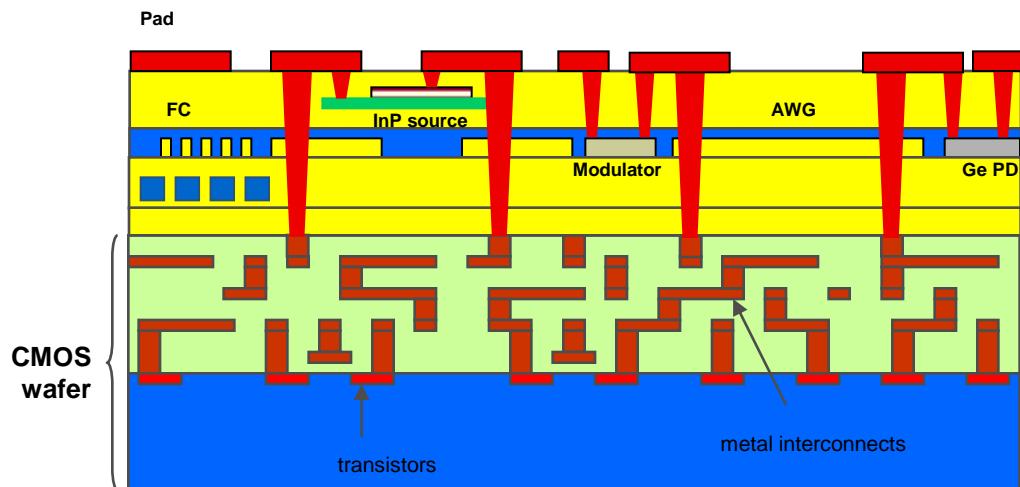
## Back-end fabrication

- 😊 On top of CMOS or in metal layers
- 😊 Serial process
- 😢 Compound yield
- 😢 Thermal budget < 400C

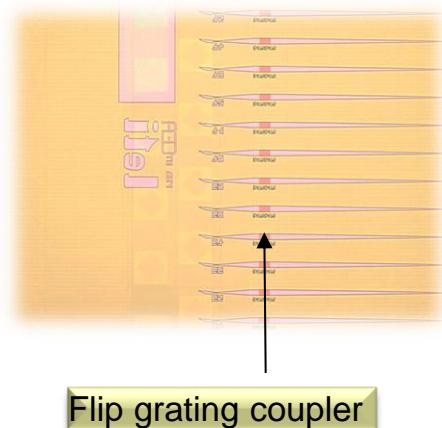
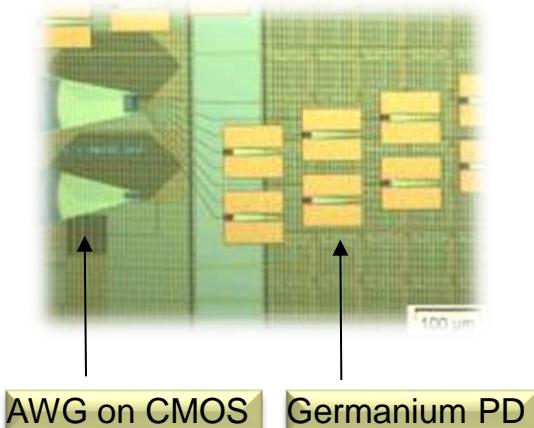
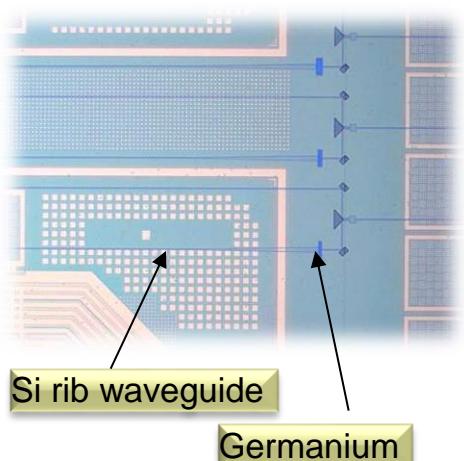


## 3D integration

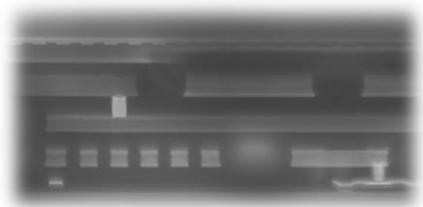
- 😊 Separate processes
- 😊 No change in CMOS Front-End
- 😊 No thermal budget!
- 😊 Other layers: MEMS, antennas
- 😢 Higher (but reasonable) parasitics



cea  
leti



- 3D integration
- Not depending on the specific node used to produce the electronic wafer



- Photonic links may replace copper links, even for very short distances
  - ✓ Silicon photonics is more and more a mature technology with the demonstration of 40Gbit/s optoelectronic devices including optical modulators and photodetectors
  - ✓ Development of silicon photonics on 300mm platform
- Advances in electronic - photonic integrated circuits (EPIC)
- New trends:
  - ✓ Low power consumption optoelectronic devices

→ [ Ge/SiGe platform on silicon  
Strained silicon photonics ]



# Acknowledgements: Funding and collaborations



Agence Nationale de la Recherche  
**ANR**

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**SILVER, MICROS, GOSPEL, MASSTOR,  
ULTIMATE, Ca-Re-Lase, POSISLOT**



**HELIOS**

*Photonics Electronics functional integration on CMOS*



**Plat4M**

*photonic libraries and technology for manufacturing*



**SASER**

*Safe and Secure European Routing*

**CARTOON**

*Carbon nanotube photonic devices on silicon*

